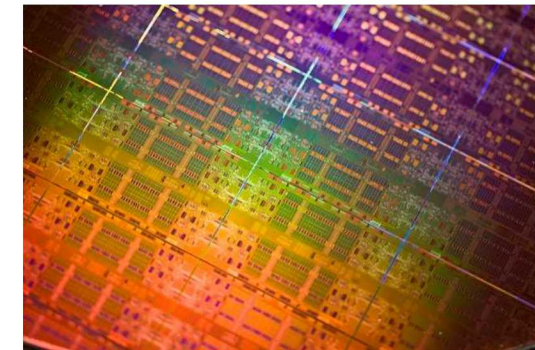
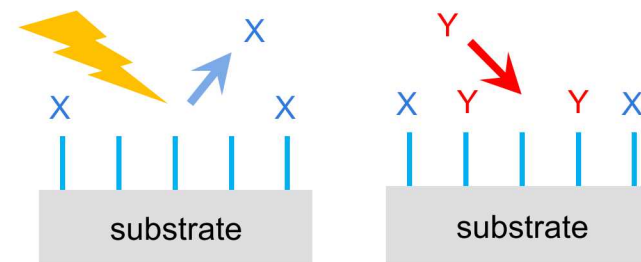
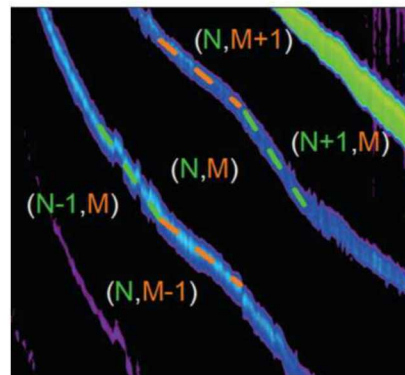
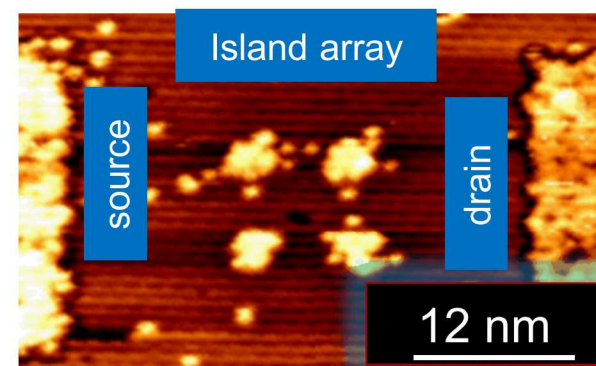


Quantum transport in a single electron transistor

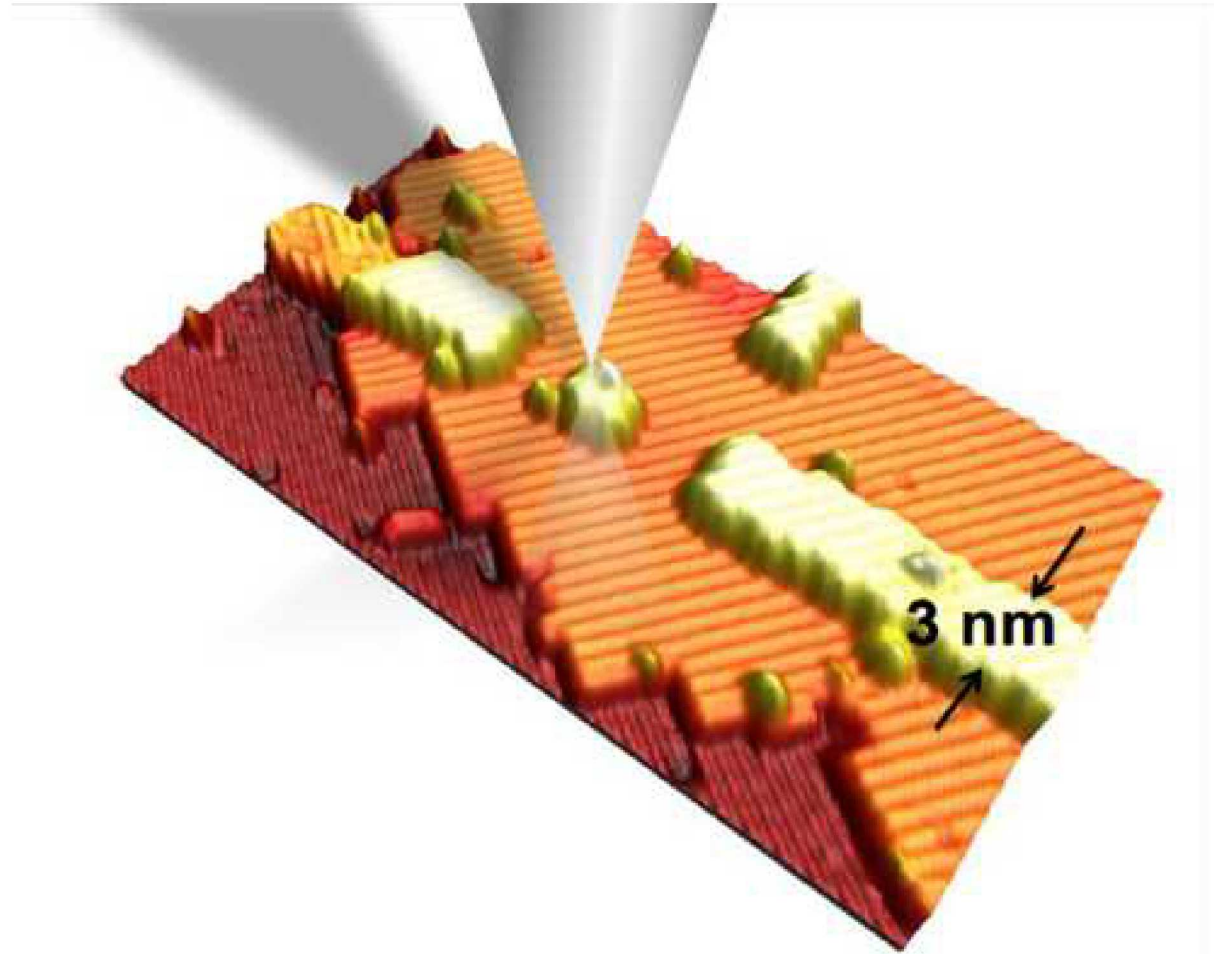
Quantum transport in a single electron transistor



Digital electronics at the atomic scale

Shashank Misra

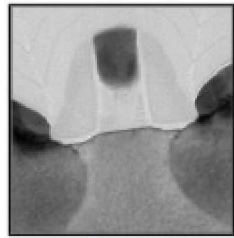
Atomic Precision Advanced Manufacturing



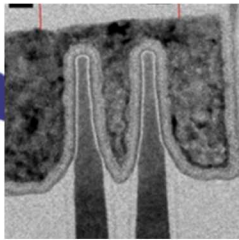
Assess the opportunities presented by having atomic-scale control over devices and processing for the digital microelectronics of the future

Where is microelectronics headed?

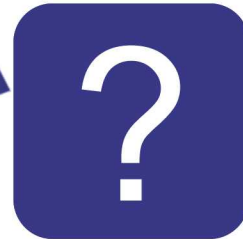
Historically, shrink transistor → more functionality and declining cost



65 nm

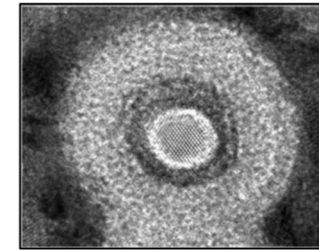


10 nm

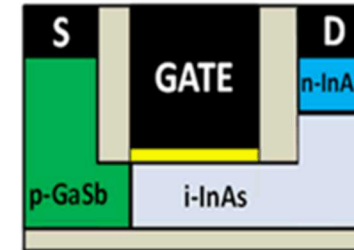


5-7 nm

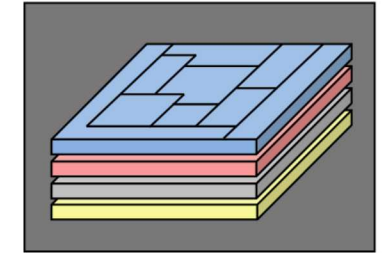
Unclear technology path.



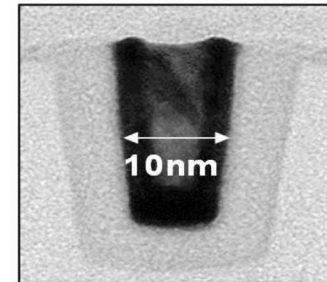
Nanowire Transistors



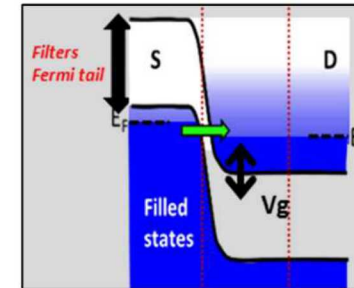
III-V Transistors



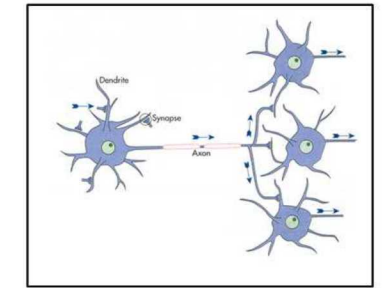
3D Stacking



Dense Interconnects



Tunnel FETs

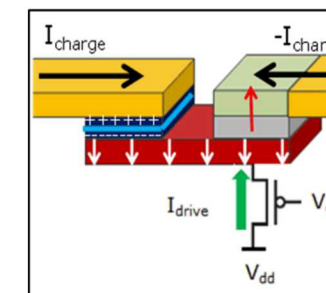


Neuromorphic Computing

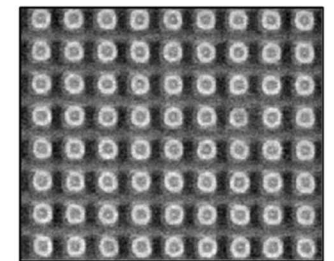


Nanosheets

Huiming Bu, IBM 2017



Spintronics

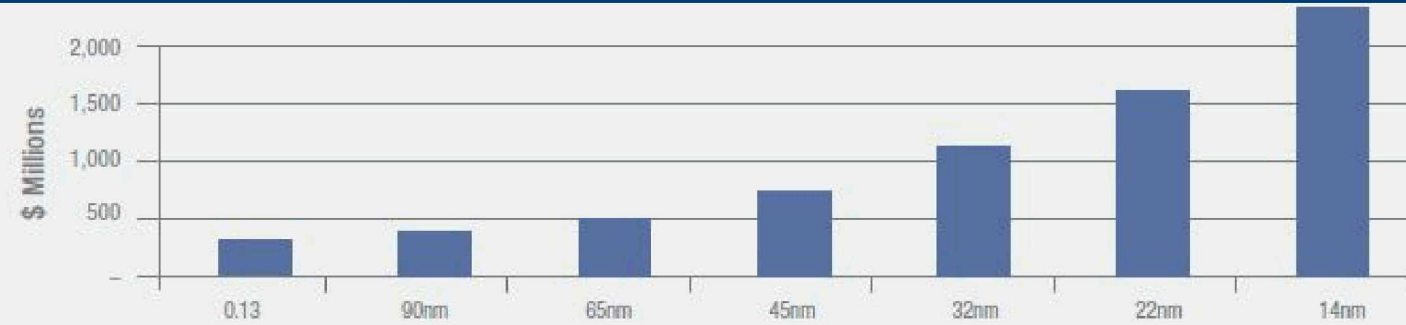


Dense Memory

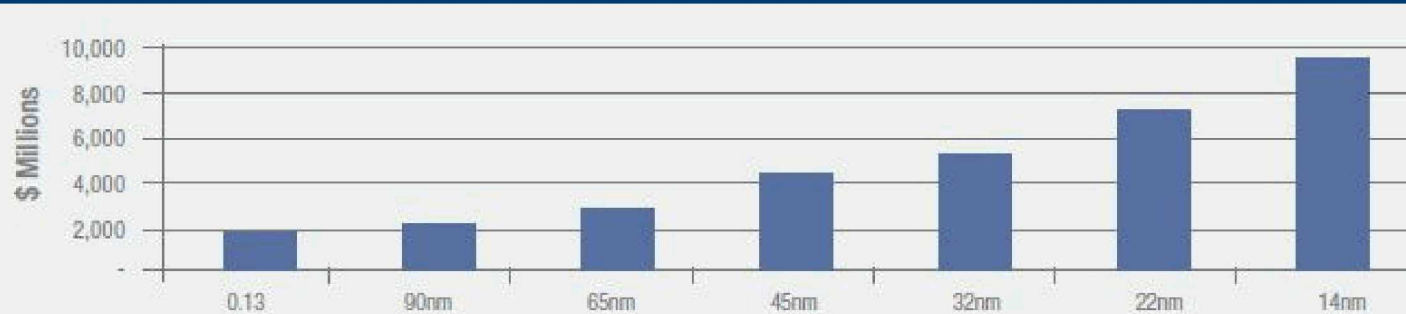
Mark Bohr, Intel 2018

Emerging risk in manufacturing-driven ecosystem

Process technology development cost by node



Fab costs by node



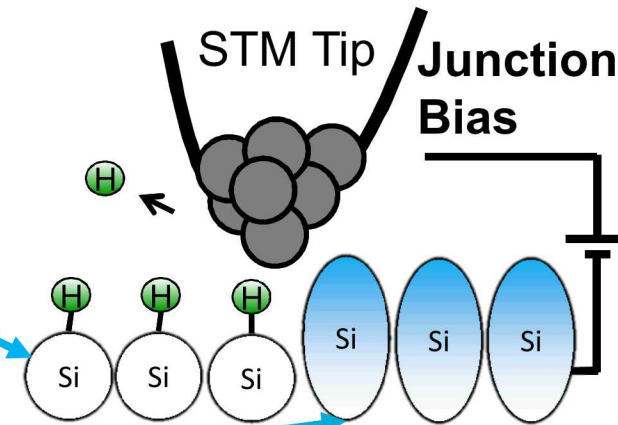
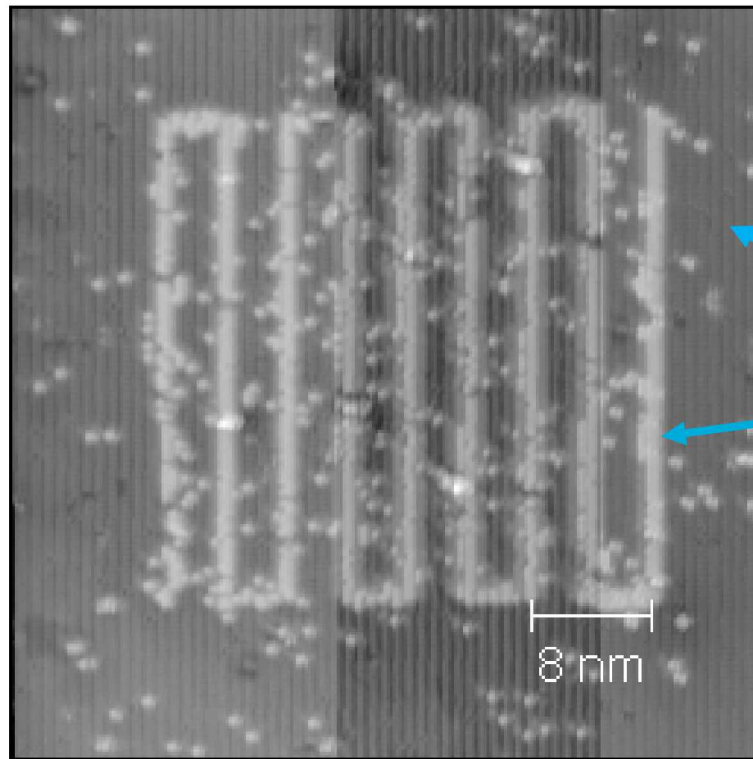
Source: Common Platform & AllxPartners Analysis

Ask what opportunities exist given atomic-scale control

How does Atomic Precision Advanced Manufacturing (APAM) work?

“Chemical contrast” at Si surface

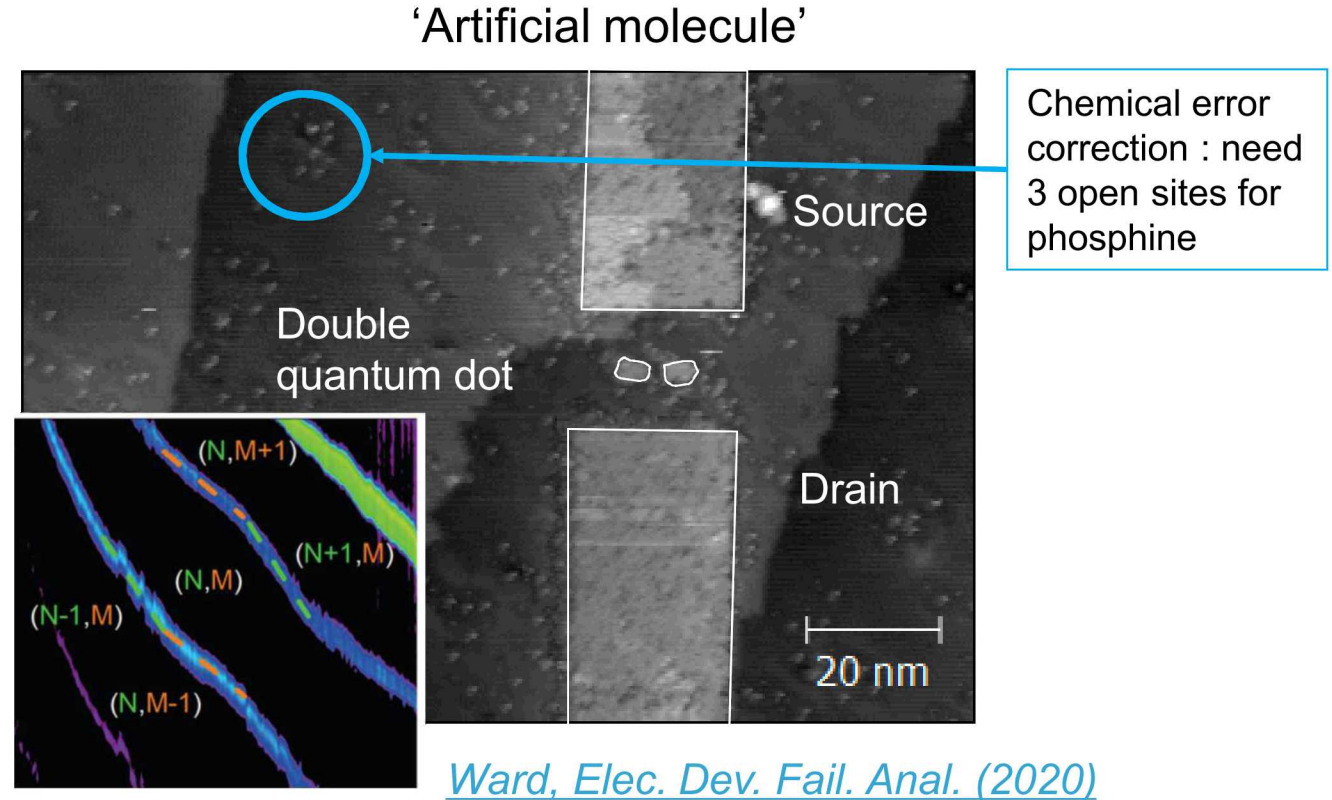
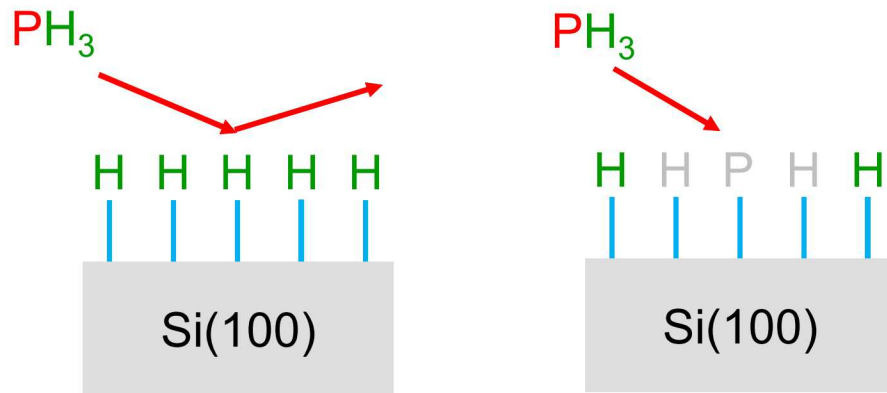
- Unterminated Si: 1 reactive bond/ atom
- H-terminated Si: unreactive



Scanning tunneling microscope (STM)
can image and pattern the surface

Area-selective chemistry with phosphine

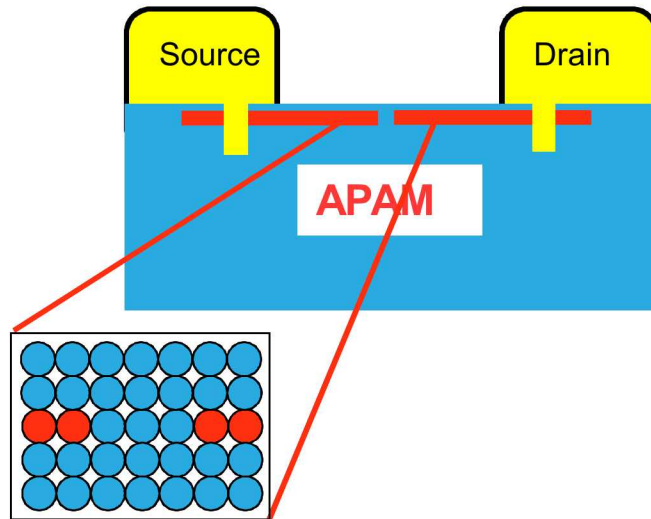
Phosphorus 'donates' an electron to silicon.



Opportunities outside of quantum demonstrations
Opportunities outside of atomic-scale widgets

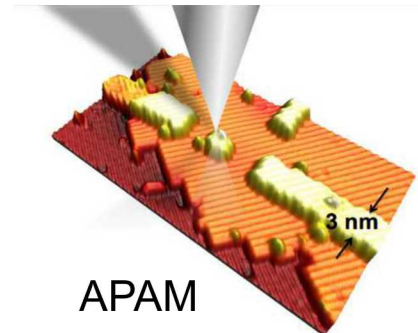
How to get to digital electronics at the atomic scale?

1. APAM devices



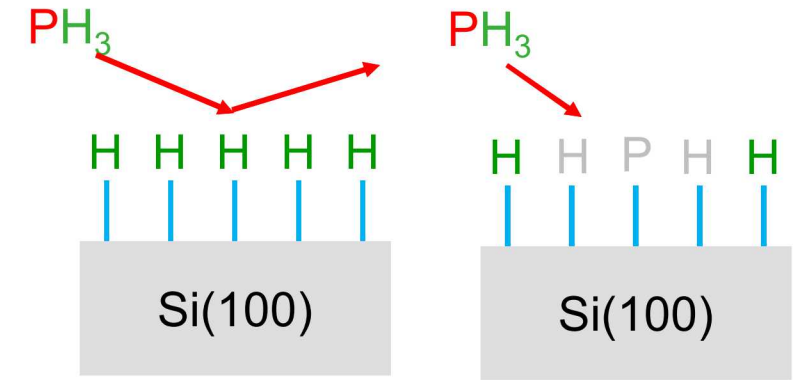
- ☐ Simple planar devices
- ☐ Only work at cryogenic temp.

2. CMOS integration



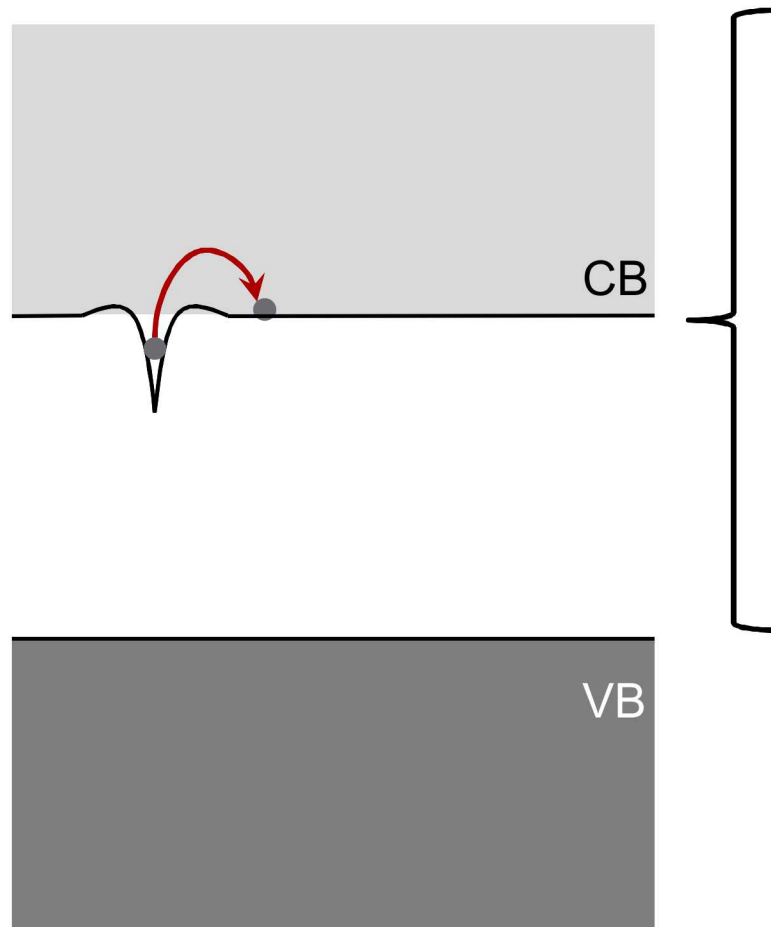
- ☐ Incompatible with CMOS workflows / parts

3. APAM toolkit

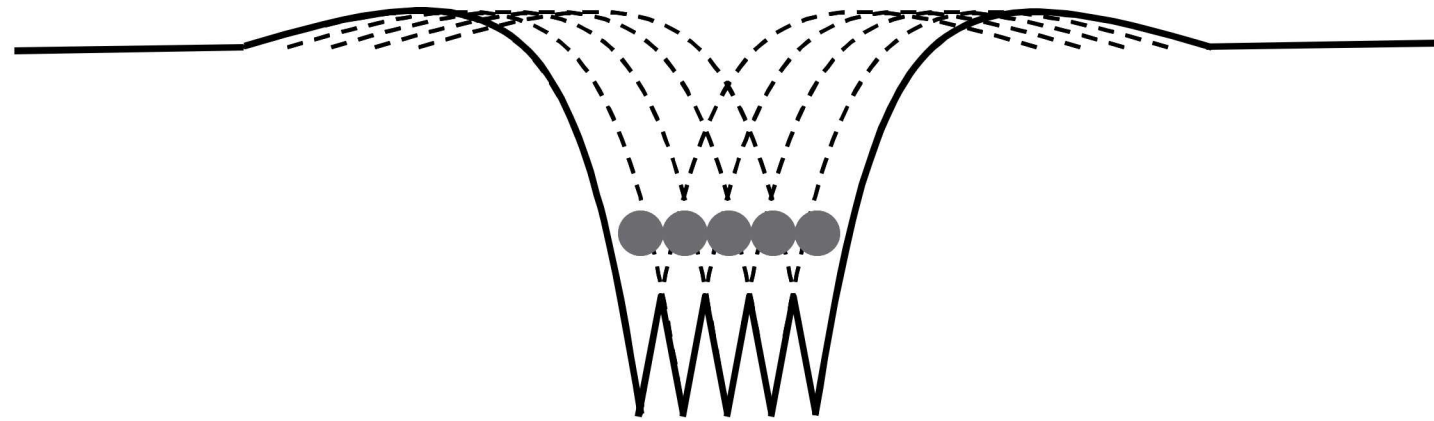


- ☐ One working chemistry

What does APAM do that's special? "Ultra-doping"



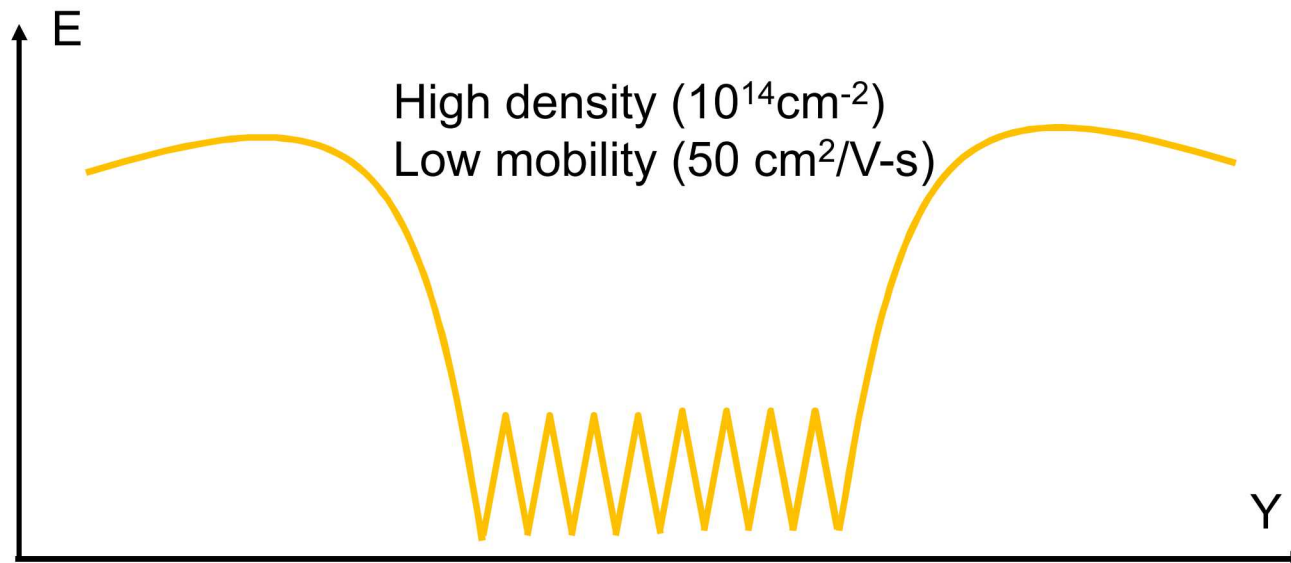
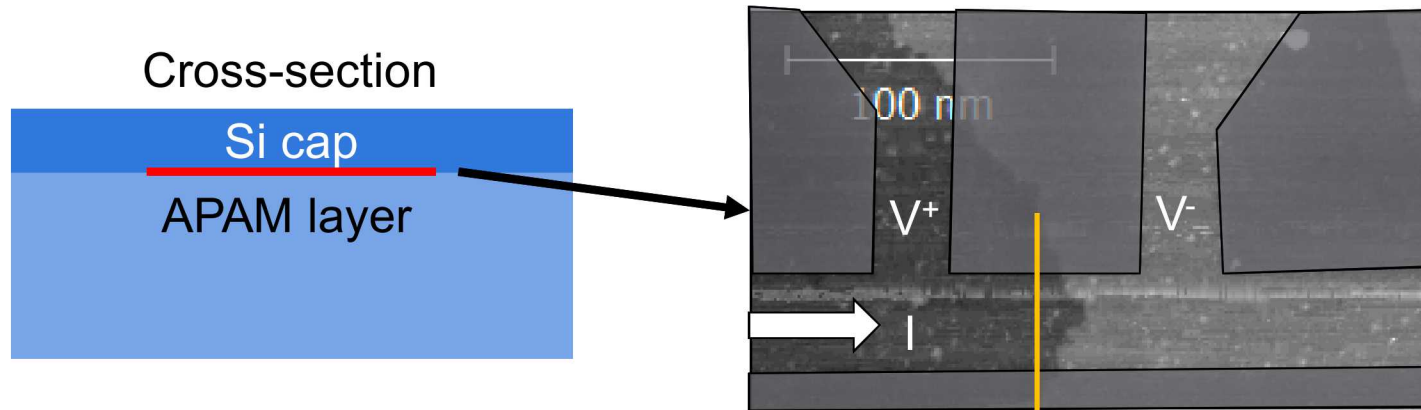
Normal doping



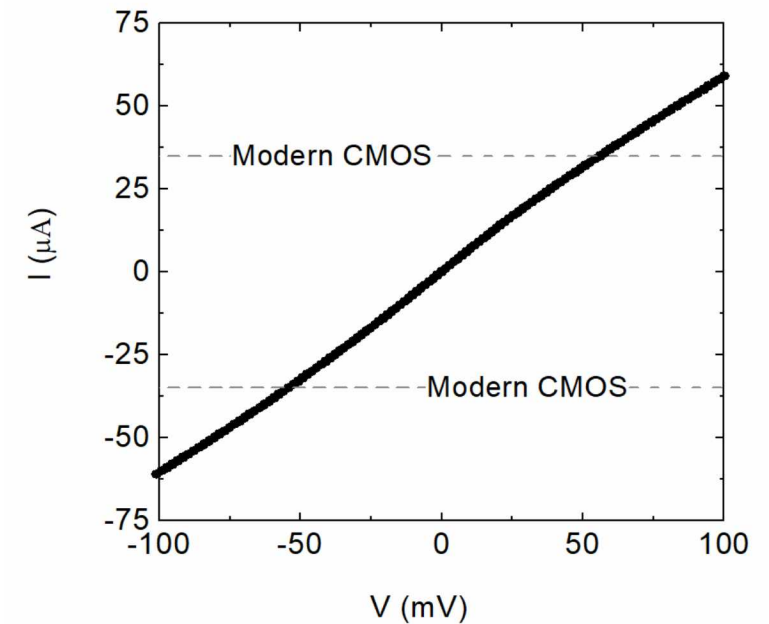
Ultra-doping: dopant potentials/
wavefunctions overlap significantly

APAM doping: 1 in 4 surface sites is a donor
Exceeds solid solubility for P in Si by 10x

Consequences: confinement

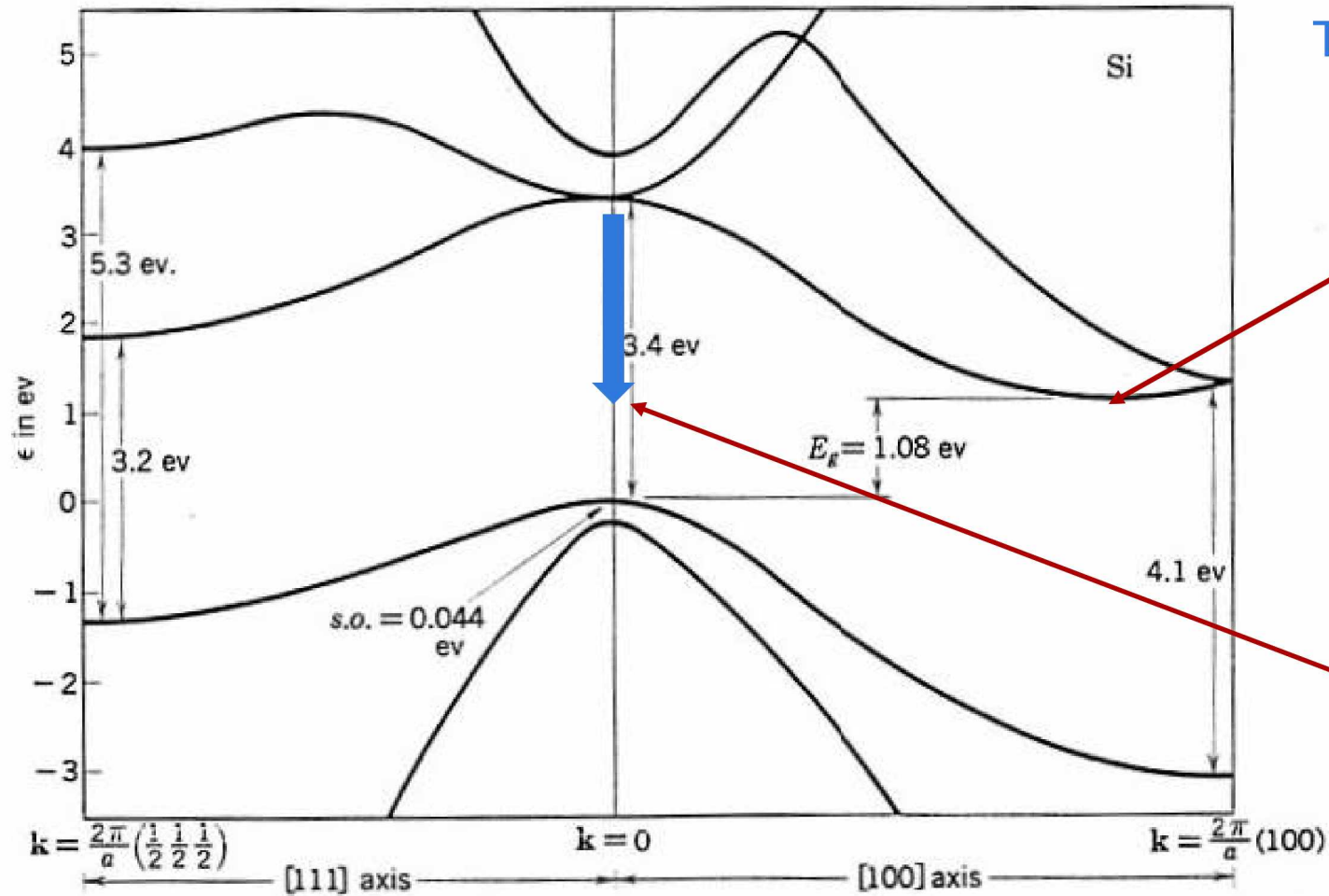


[*Ward, Elec. Dev. Fail. Anal. \(2020\)*](#)

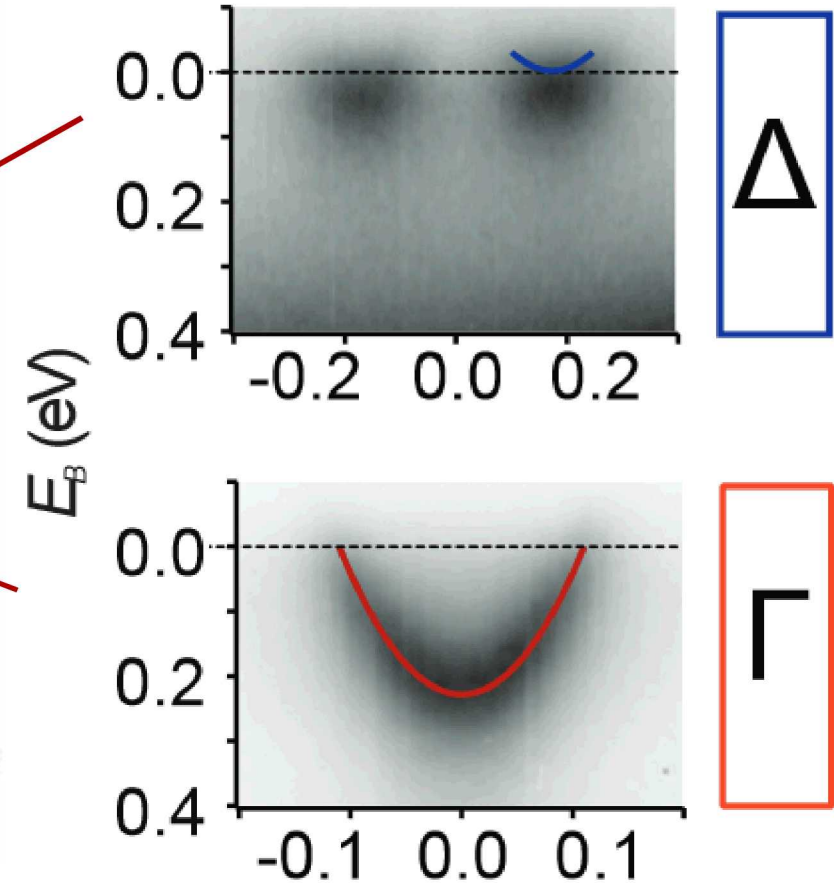


Dopants give you confinement
Extremely high current density.

Consequences: electronic structure

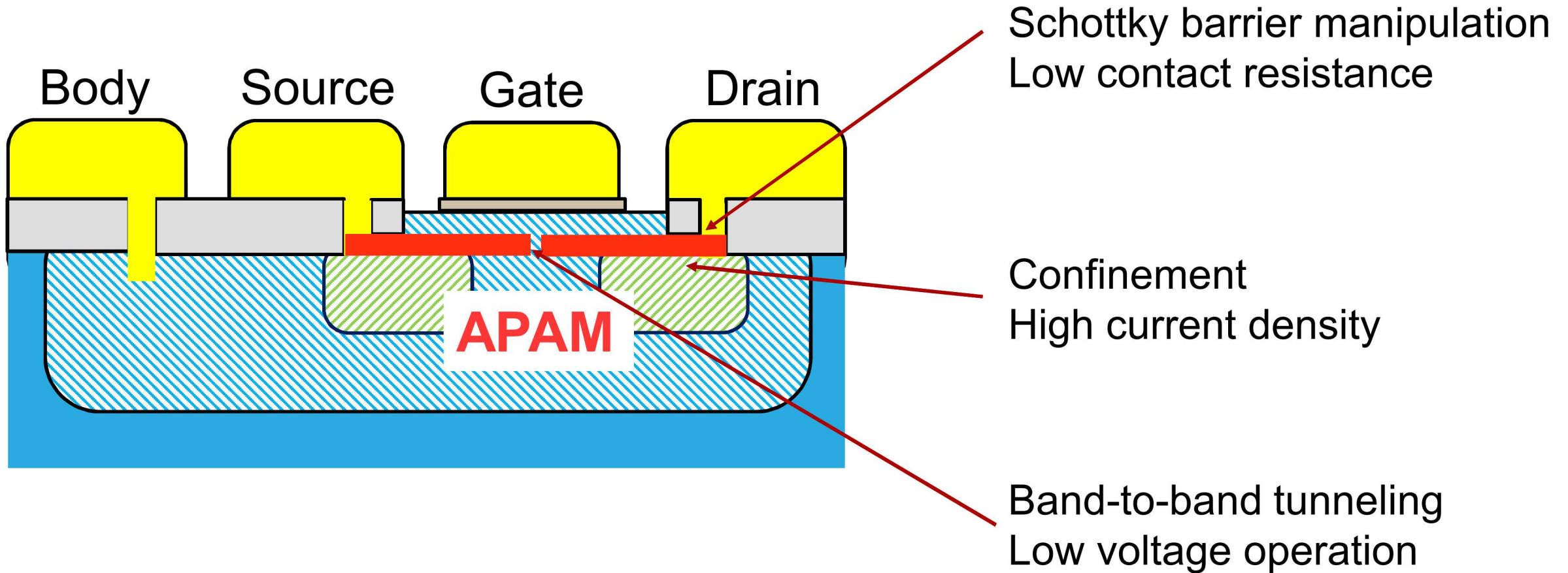


This isn't really silicon like you know it.



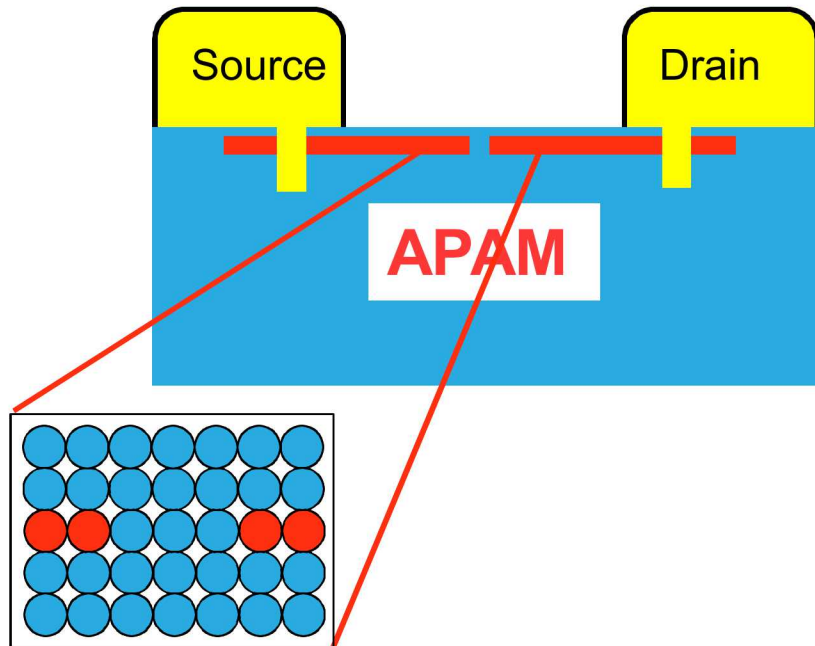
[Holt, arXiv:1911.08274](https://arxiv.org/abs/1911.08274)

APAM-inspired transistor



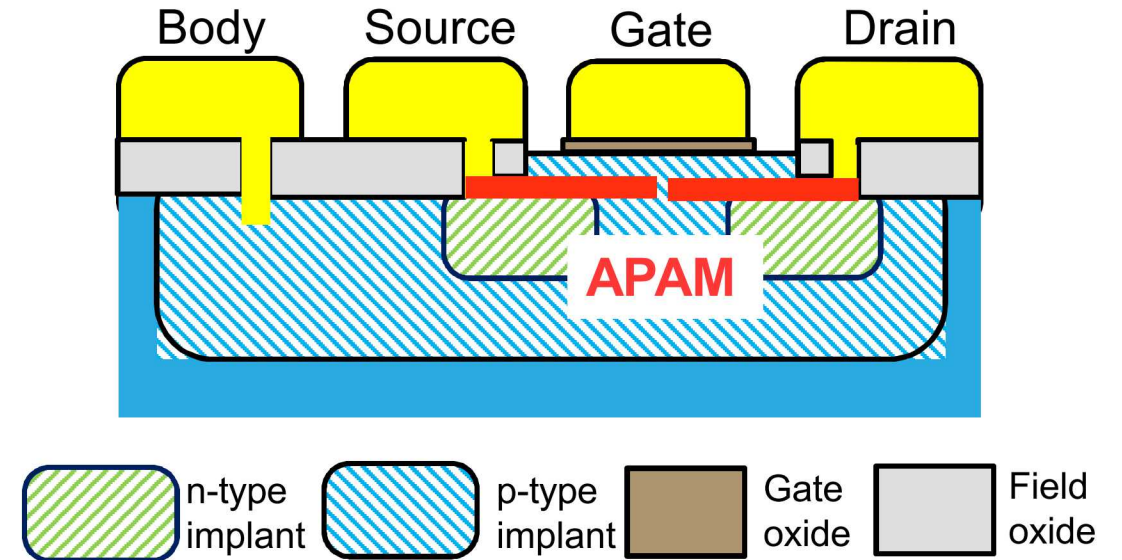
Can you make a 'real' transistor with APAM?

Now (3 US labs, 6 labs worldwide)



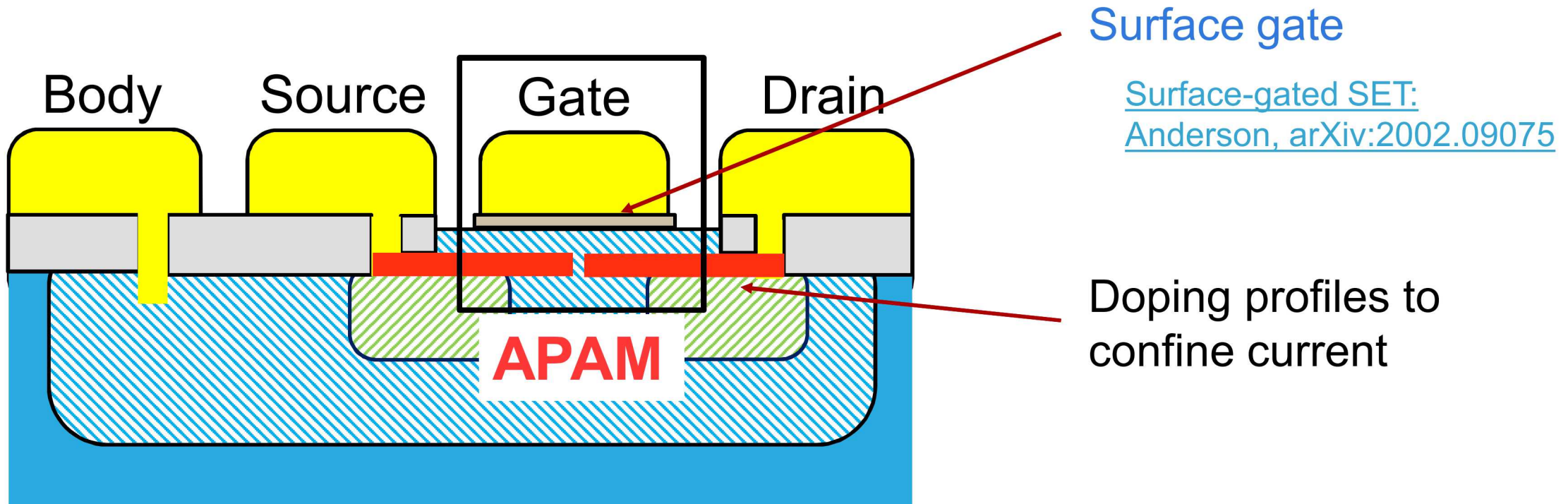
- Only works at cryogenic temperatures
- Devices consist only of phosphorus!

Desired future state



- Works above room temperature
- Device is complex

“Real” APAM transistor

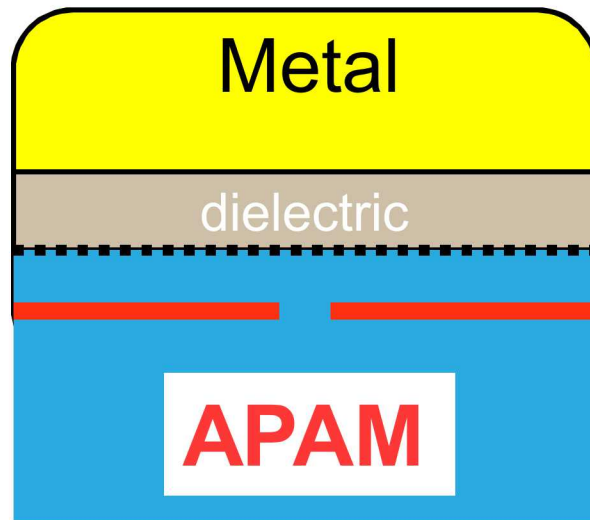


Surface gate challenge: thermal budget

Dopants readily diffuse ~ 350 – 550 °C
Low defect silicon oxide needs ~ 800 °C

Modern high-k dielectrics require temperatures that are accessible

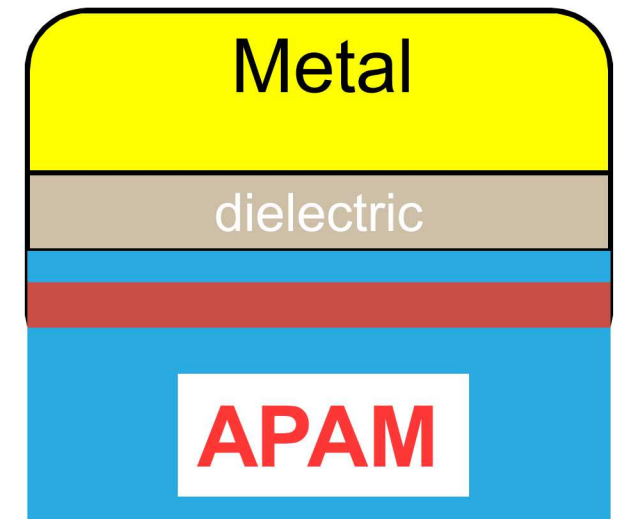
Low temperature



Poor quality interface shields gate
Dopants have remained in place

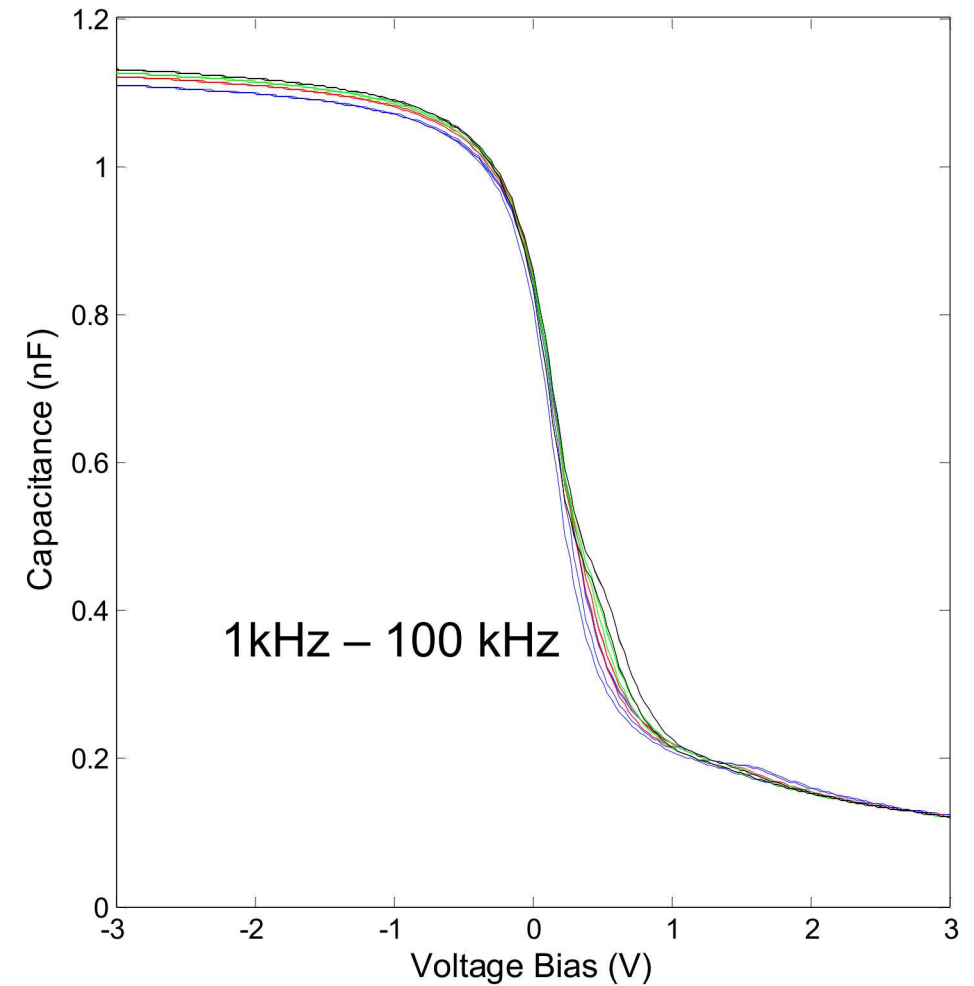
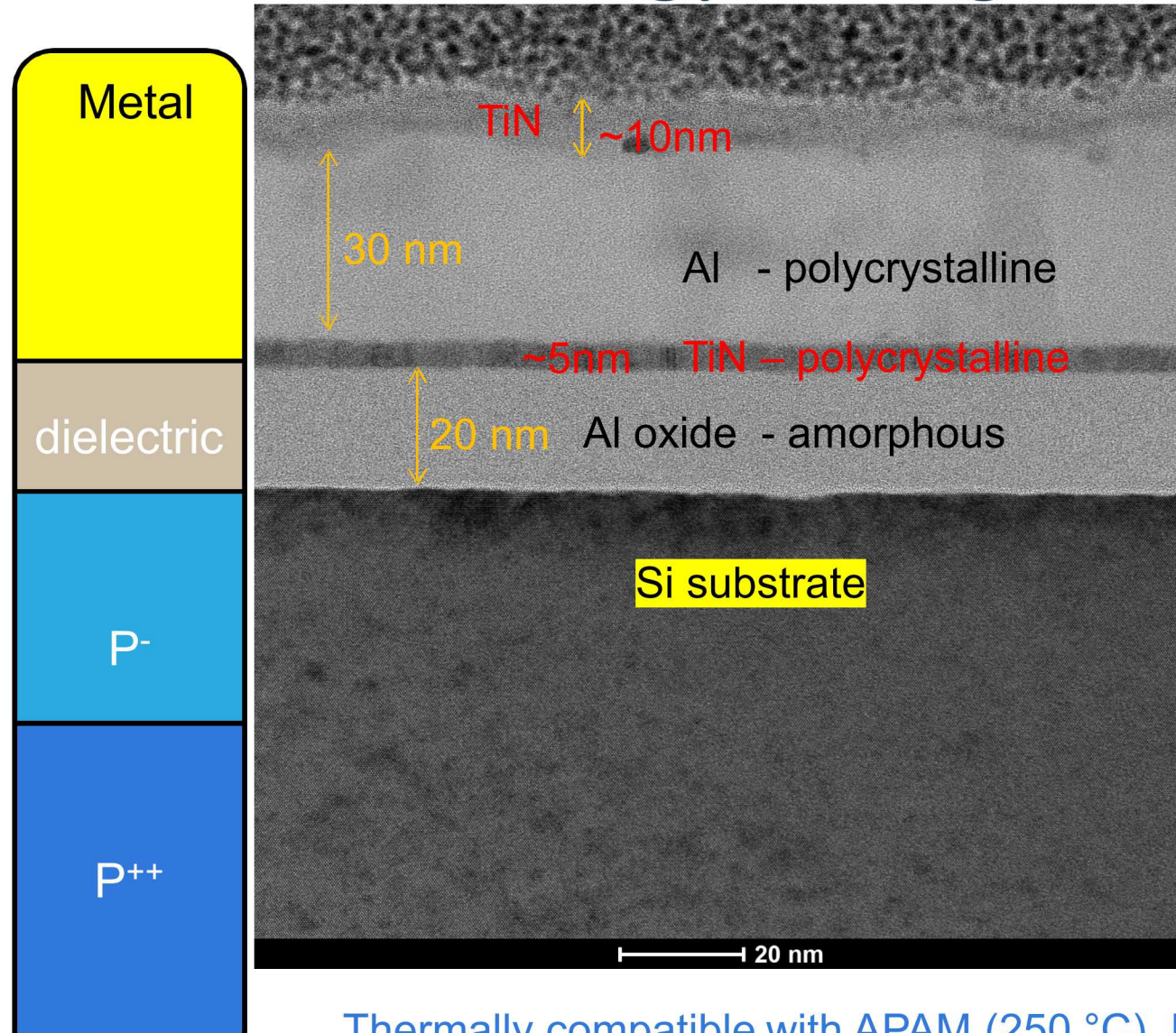
Is there a sweet spot?

High temperature



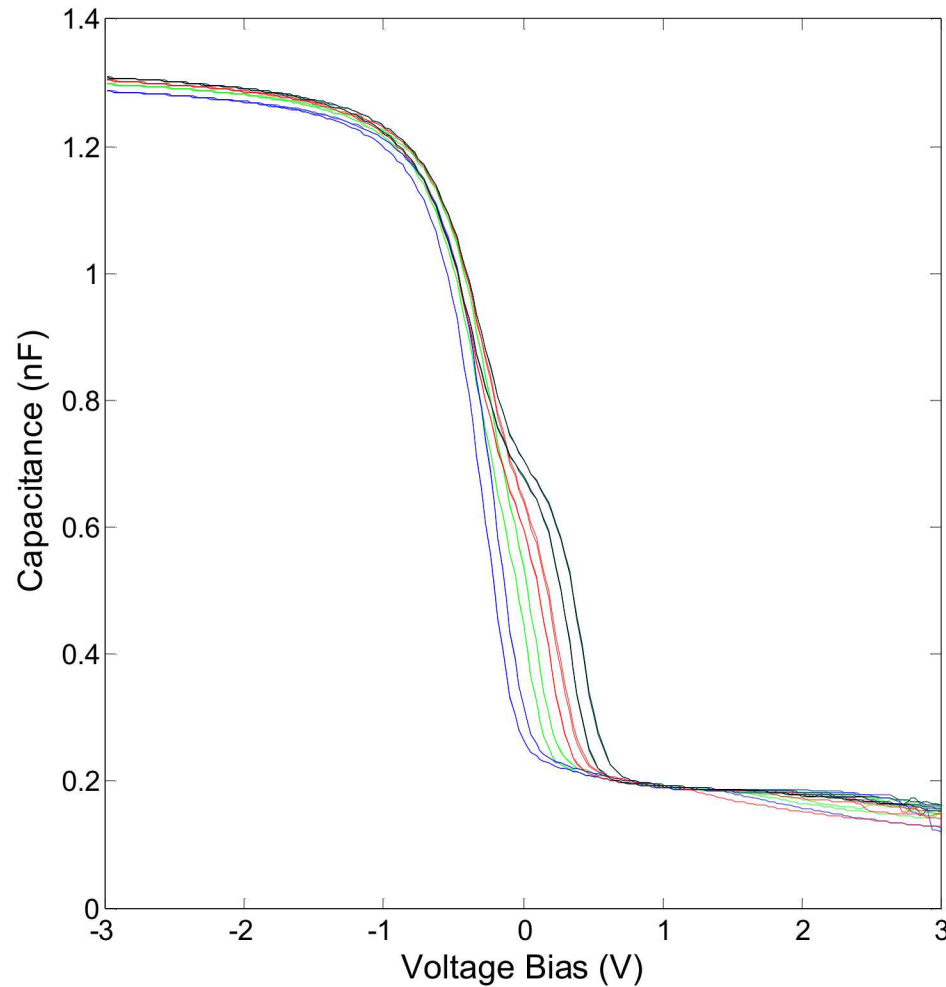
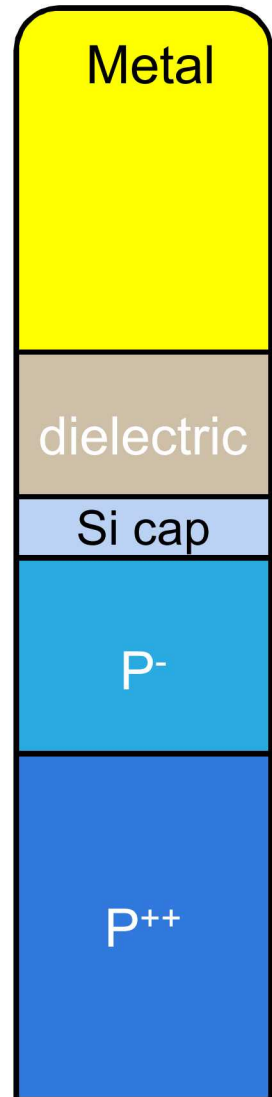
High quality interfaces
Dopants have diffused

Follow strategy for high-k/metal gates

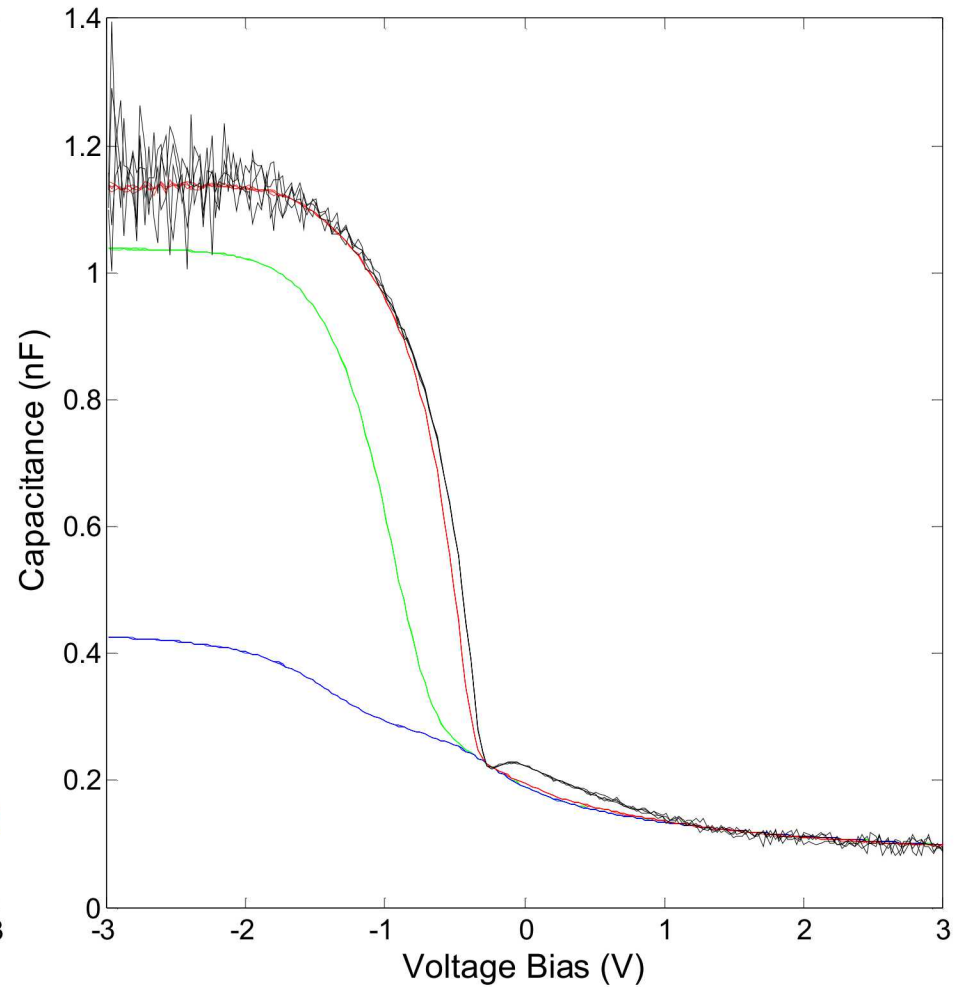


Thermally compatible with APAM (250 °C). Low density of interface defects: $4 \times 10^{10} \text{ cm}^{-2}$

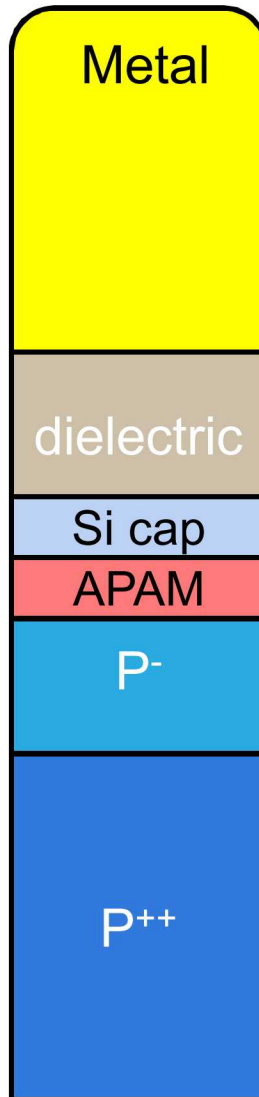
First-ever CV curve on an APAM layer



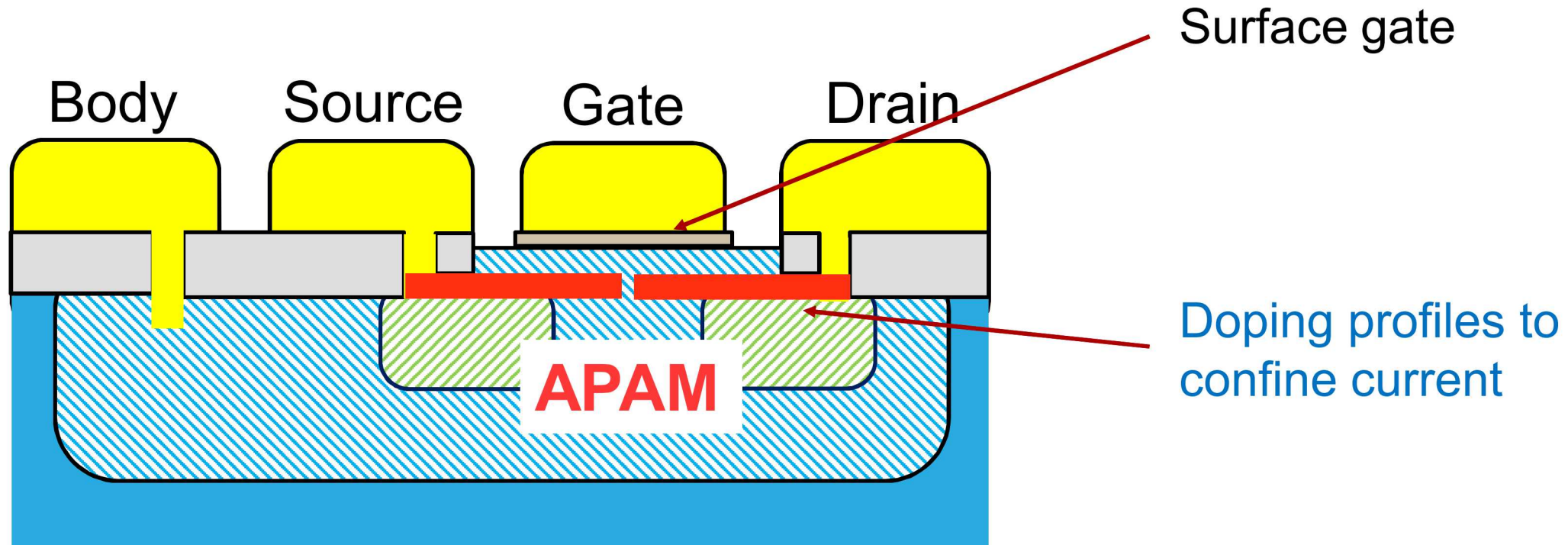
Surface charge: $1 \times 10^{11} \text{ cm}^{-2}$



Soon: finite frequency TCAD model



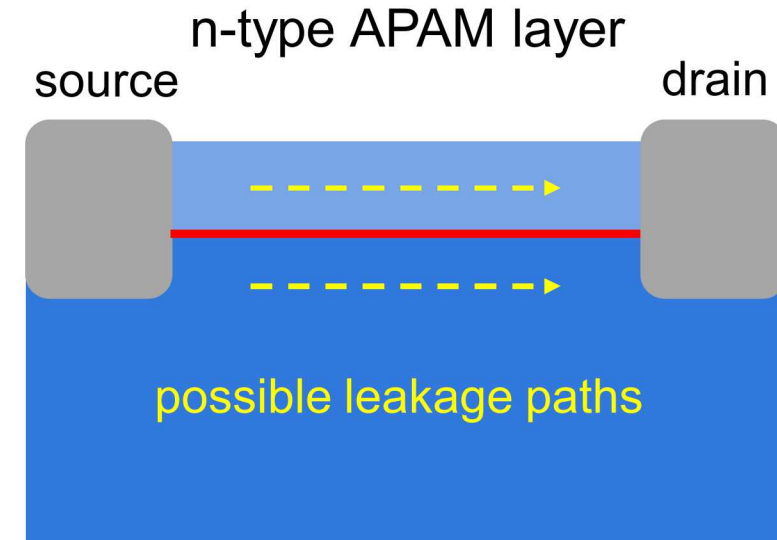
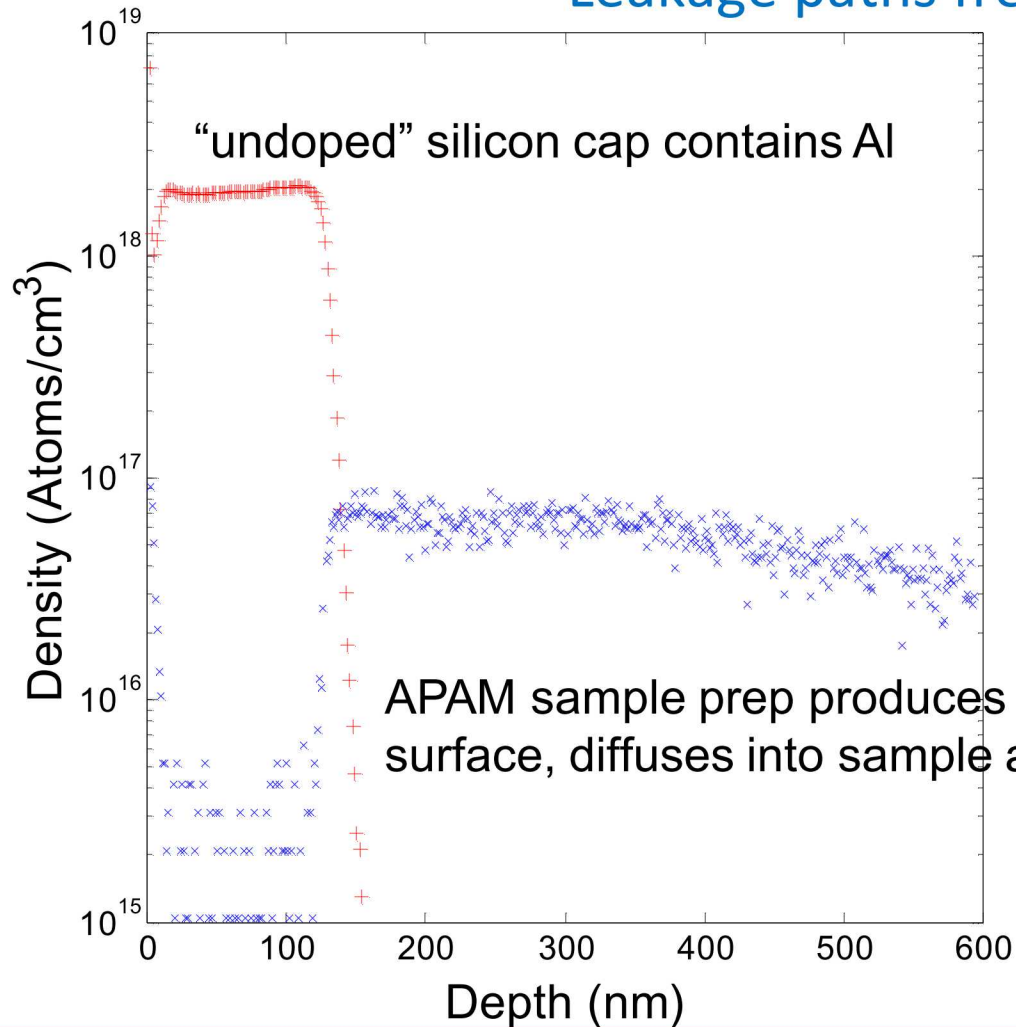
“Real” APAM transistor



Room Temperature Device Operation

Unintentional doping of cap and substrate

Leakage paths freeze out only at low temperatures

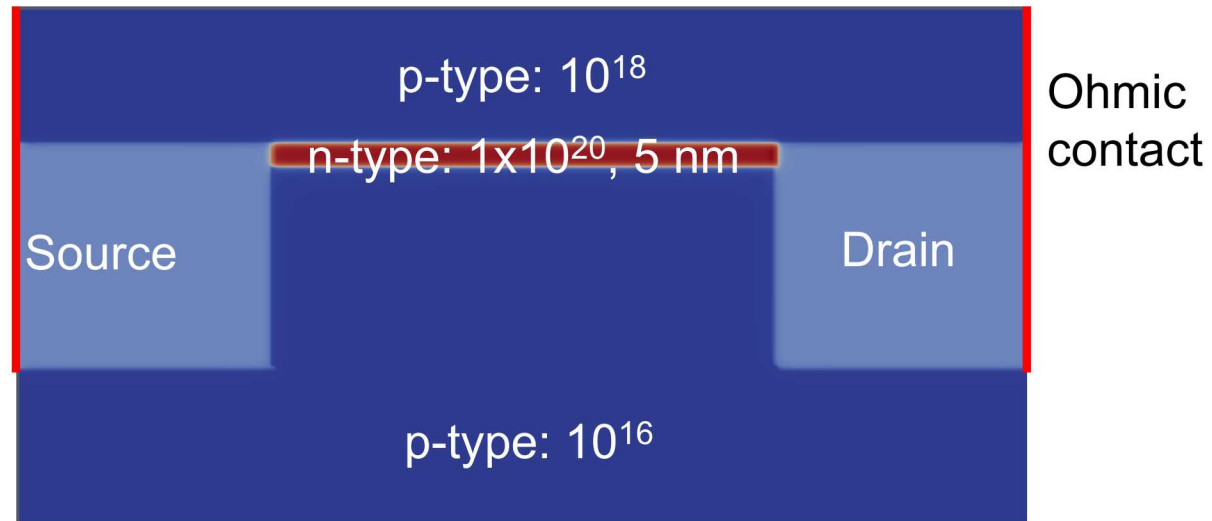


- Aluminum
- Silicon cap
- Phosphorus
- Silicon substrate

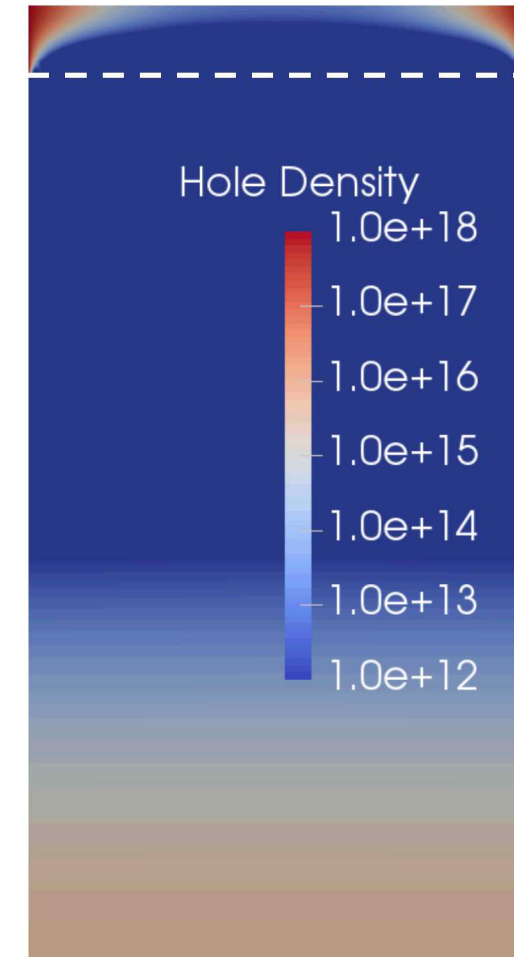
TCAD Simulations

APAM layer depletes the substrate and cap

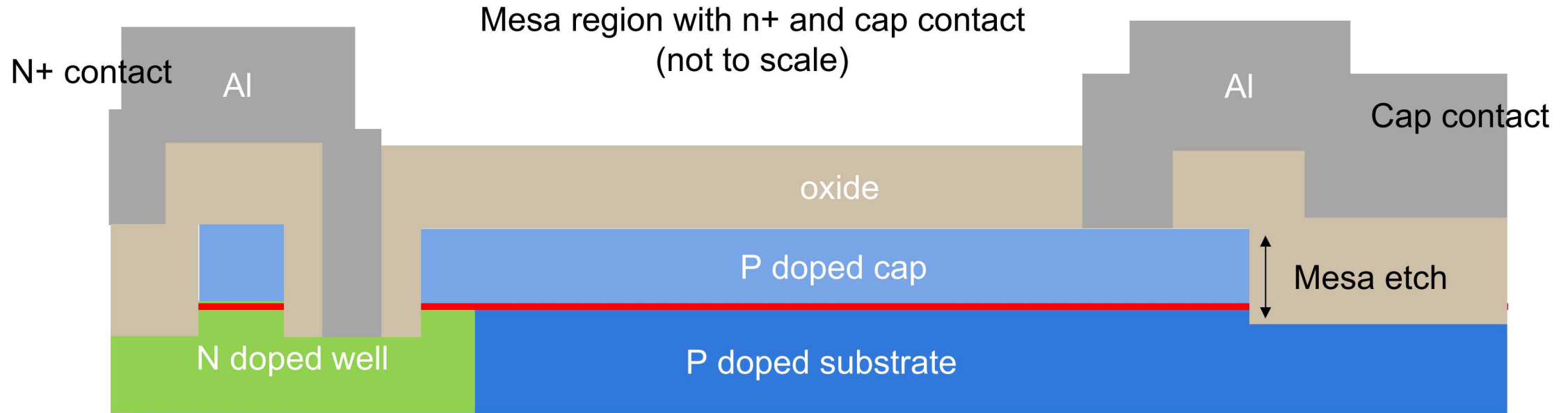
Simulation Structure



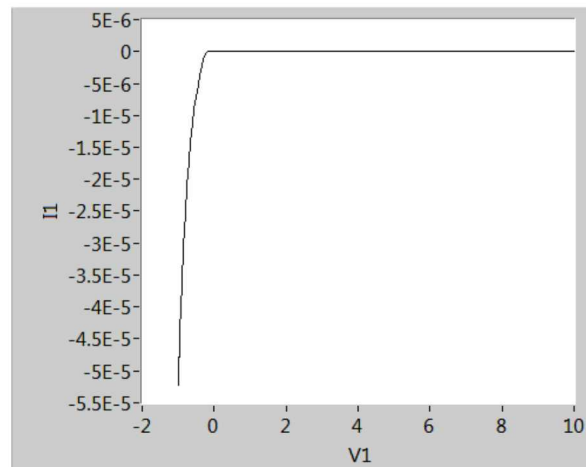
Hole Density from TCAD



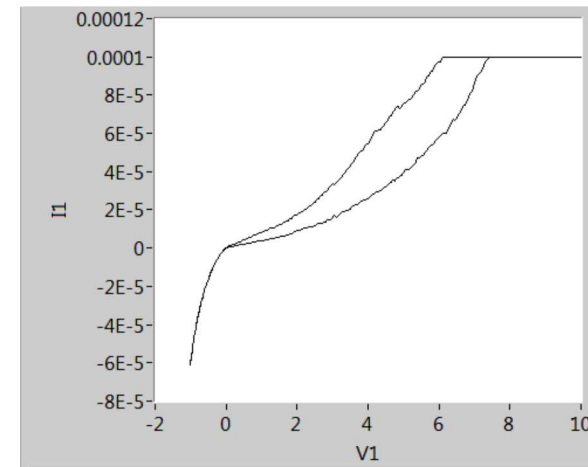
Contact isolation



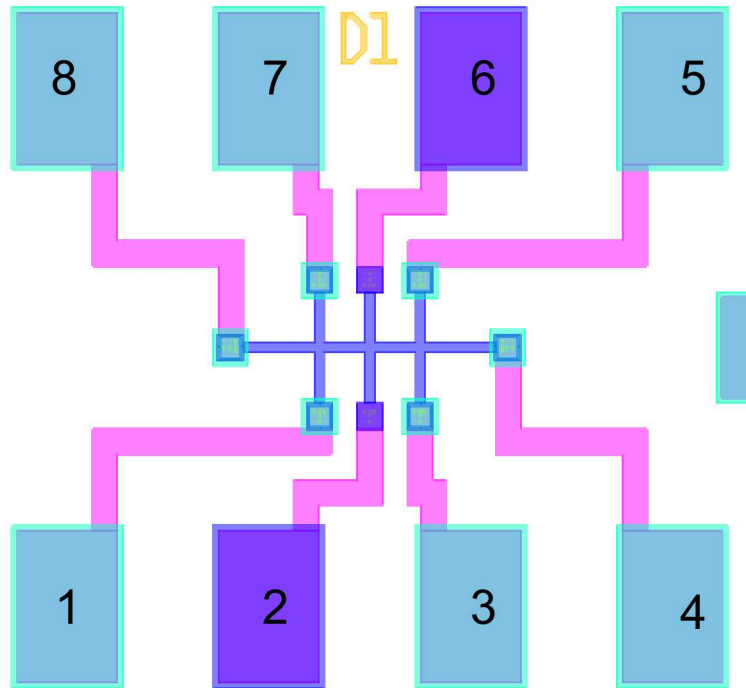
After wire bonding
25 g force



After wire bonding
35 g force

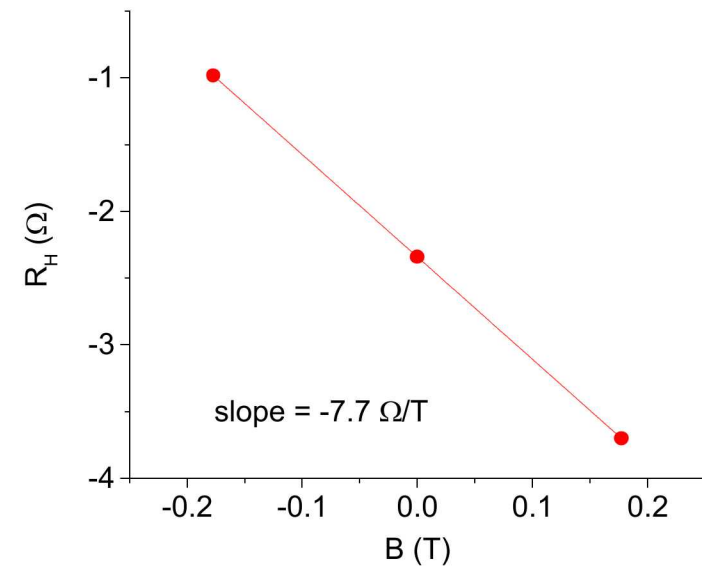


1st measurement of APAM wire at room temp.



R_{xx} : 4.80 mV/450 nA

(20-40 nA leakage at 1V)



Unclear why density goes down,
mobility stays same.

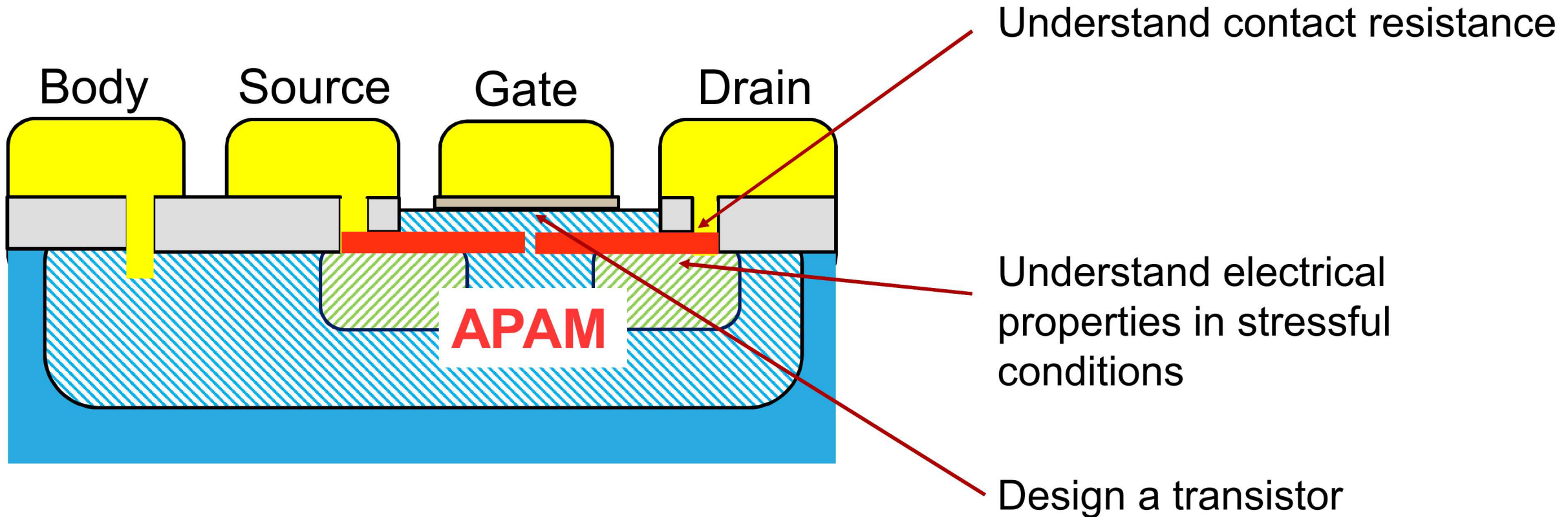
Agrees with IR measurements

Katzenmeyer, in submission to JMR (2020)

21

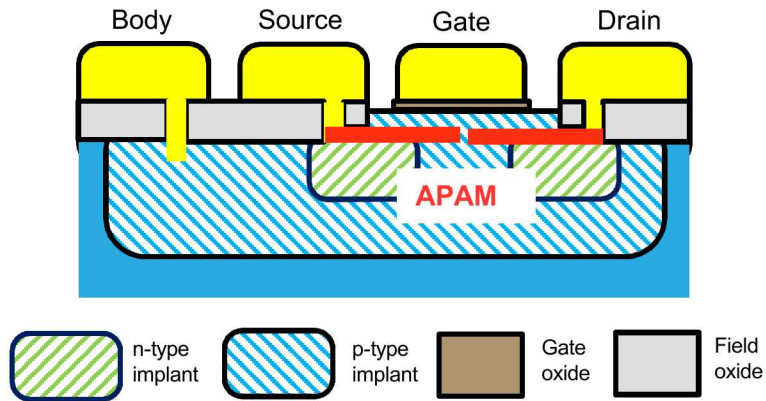
Temperature	Resistivity	Carrier density	Mobility
4 K	600 Ω/sq	$1.7 \times 10^{14} \text{ cm}^{-2}$	55
293 K	1070 Ω/sq	$0.8 \times 10^{14} \text{ cm}^{-2}$	65

What's next?



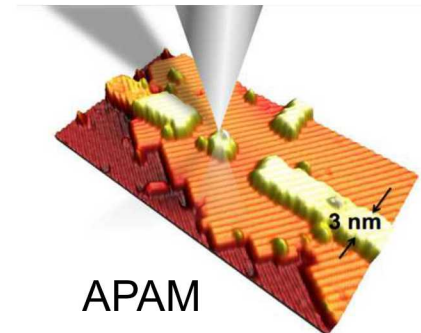
How to get to digital electronics at the atomic scale?

1. APAM devices



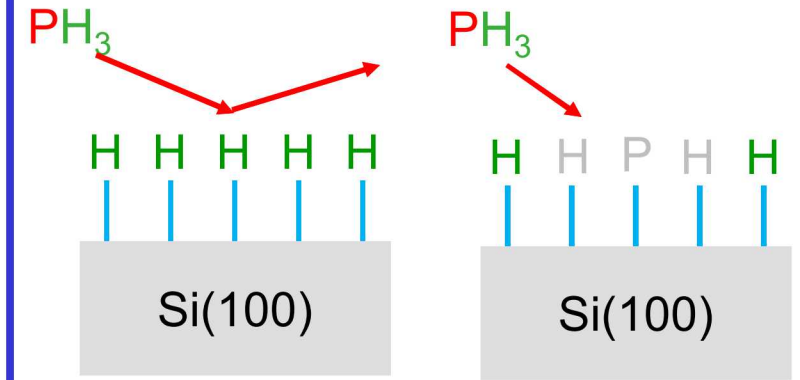
- ✓ Surface gated APAM devices
- ✓ Operate at room temperature
- ❑ APAM transistor

2. CMOS integration



- ❑ Incompatible with CMOS workflows / parts

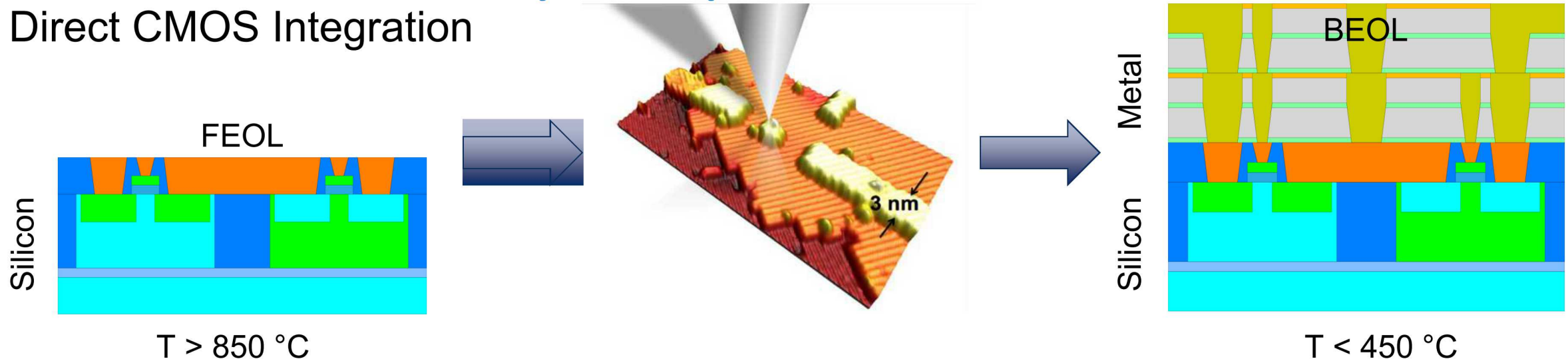
3. APAM toolkit



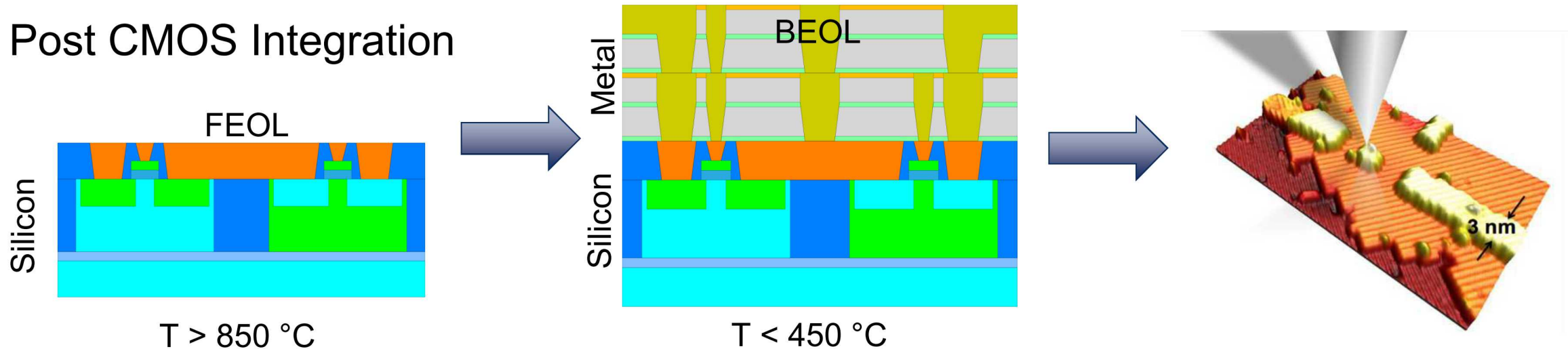
- ❑ One working chemistry

Is APAM thermally compatible with CMOS fab?

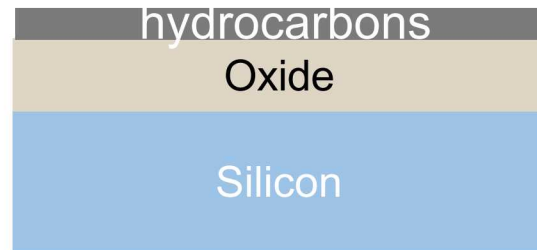
Direct CMOS Integration



Post CMOS Integration



APAM process flow



1200 °C

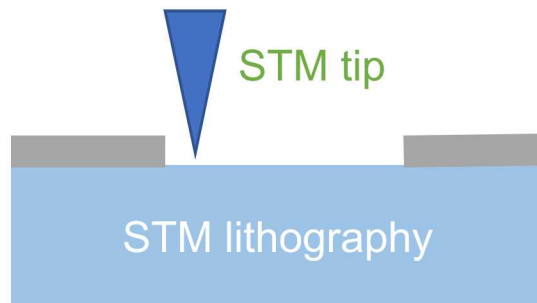
Sample clean

270 °C

Hydrogen termination

Ultra-high vacuum

High-temperature clean destroys anything on chip before APAM.



STM lithography

300 °C

Phosphorus incorporation

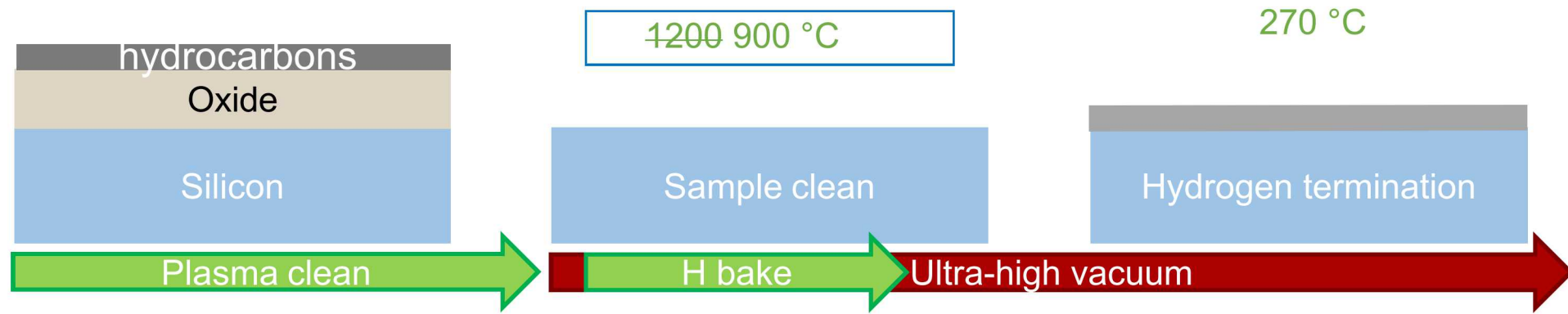
300 °C

Silicon capping

Ultra-high vacuum

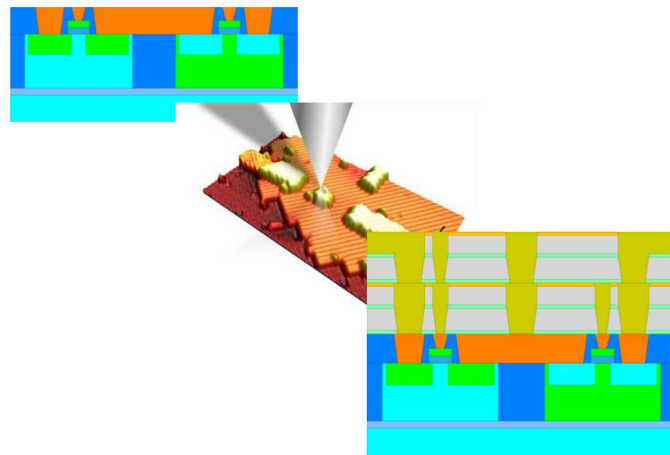
APAM will start to diffuse above 350 – 550 °C

APAM process flow

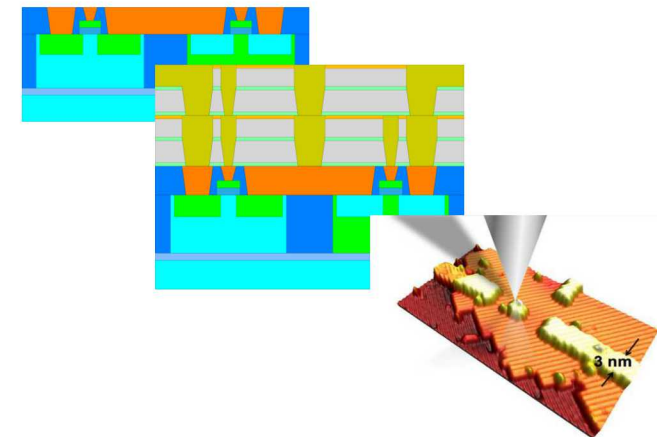


[Ward, Appl. Phys. Lett. \(2017\)](#)

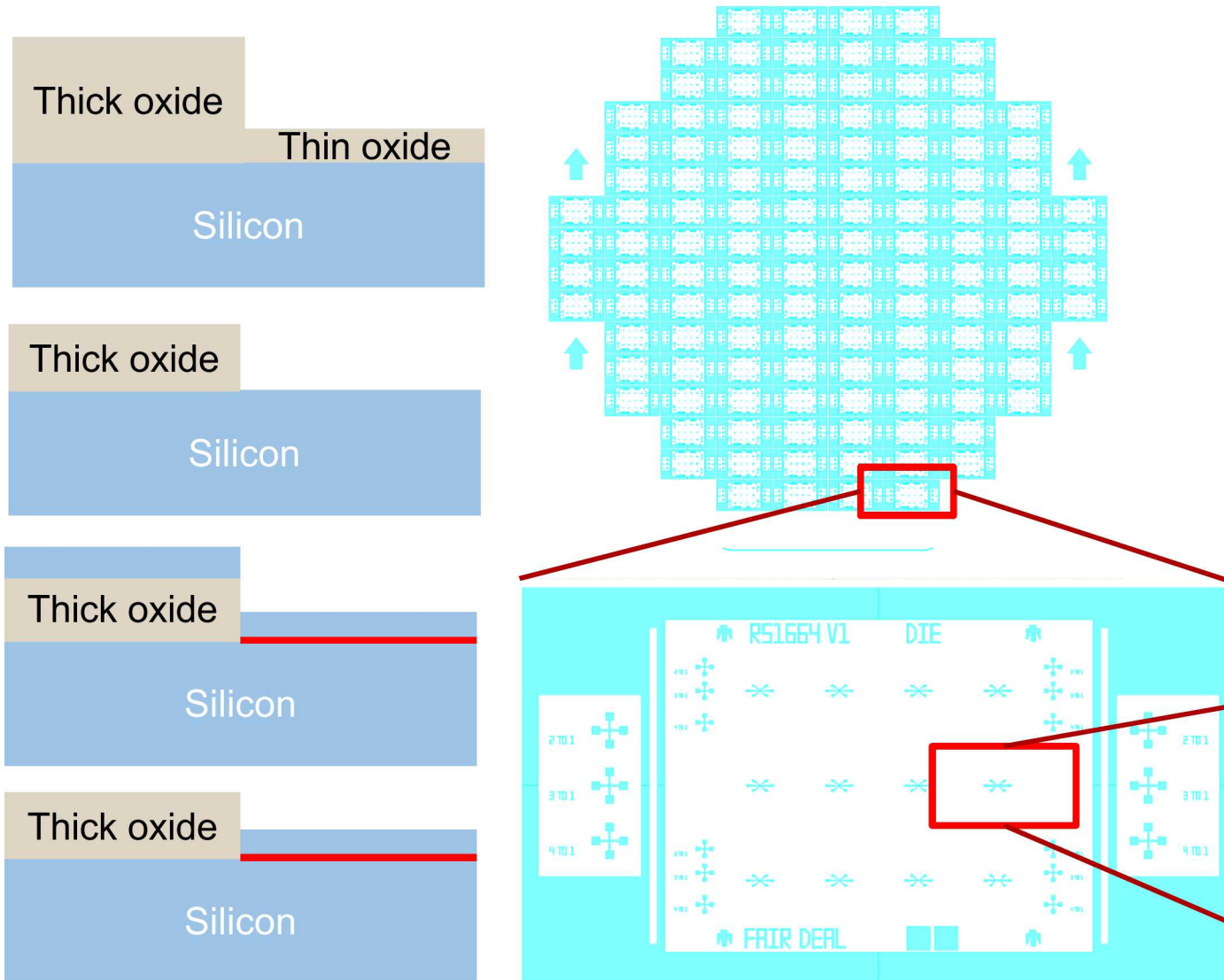
Direct Integration: can we do wafer-scale APAM processing?



Post-CMOS integration: how low can we drive down process temperatures, even with sub-optimal results?



Scale APAM using hard masks



Oxide film + thermal prep works.

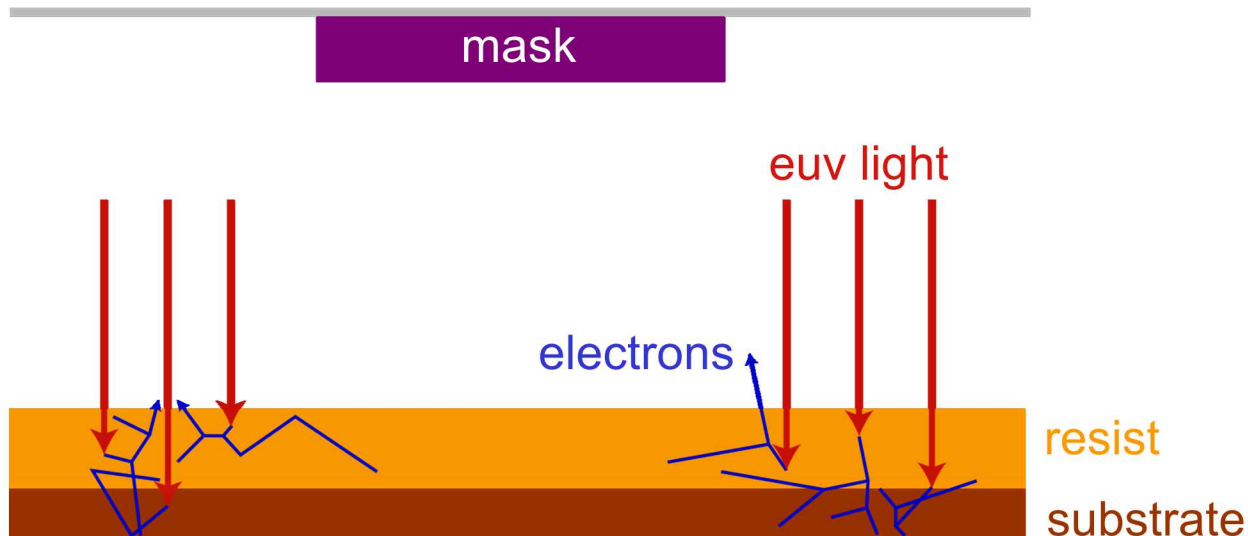
For CMOS integration –

- Nitride films
- Sputter clean
- Check local interconnects survive

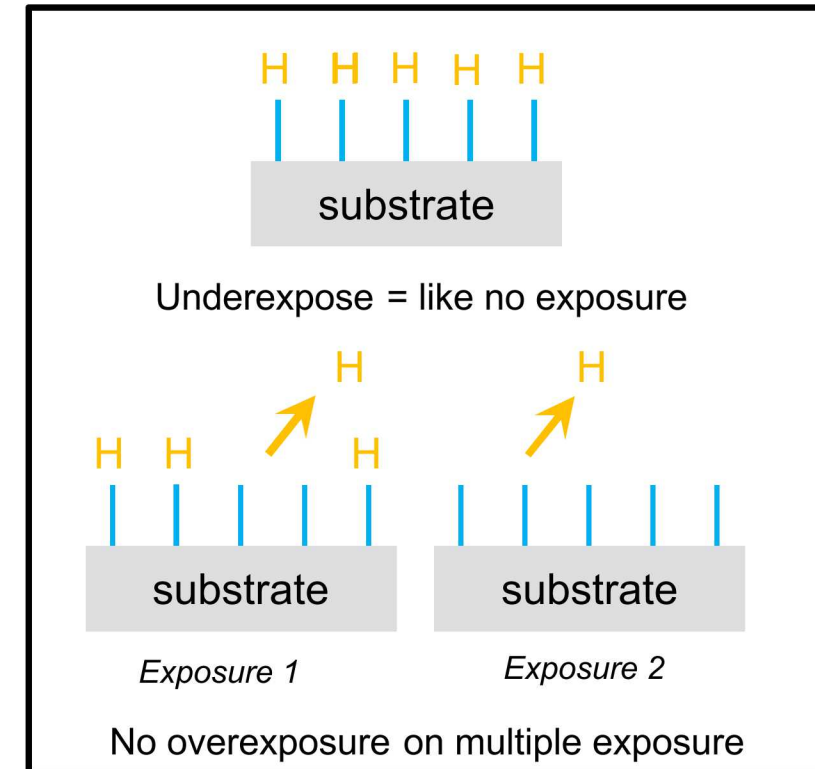
Not just 'atom-sized transistors'... atomic-scale processing

Traditional polymer resist

- Shot noise of light
- Statistics of e- generation
- Statistics of polymers



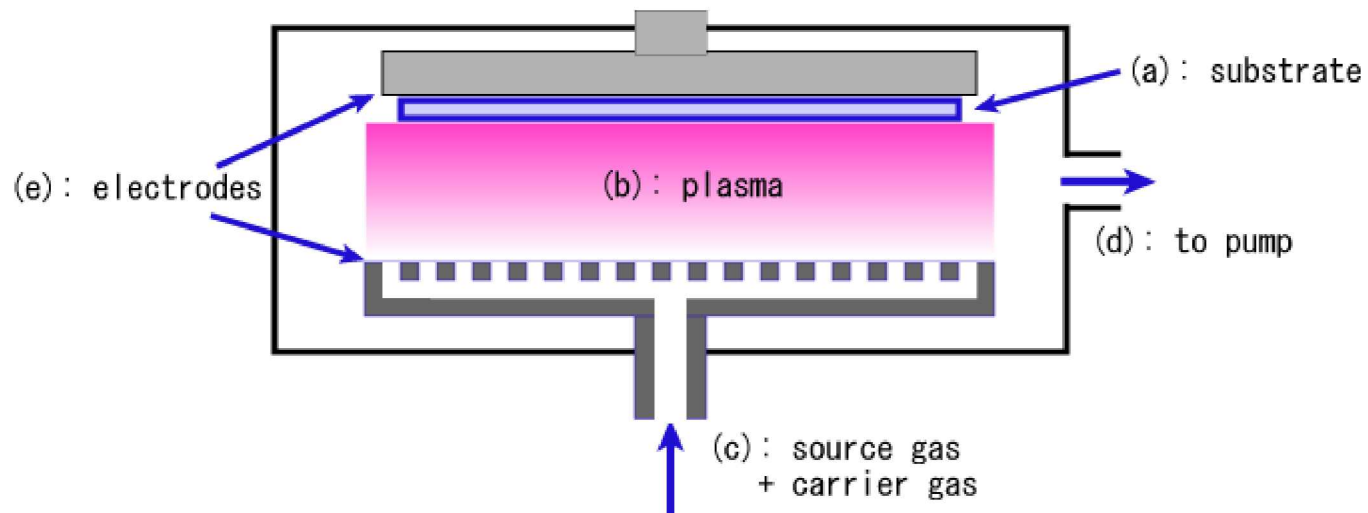
Atomic-scale resist



- Can't be over-exposed or under-exposed
→ solves problems with shot noise
- Stable to arbitrary pitch
- [*Katzenmeyer, Proc. SPIE \(2020\)*](#)

Scale APAM process

Wafer-scale processing by adding on
to existing tool (ALD or CVD)

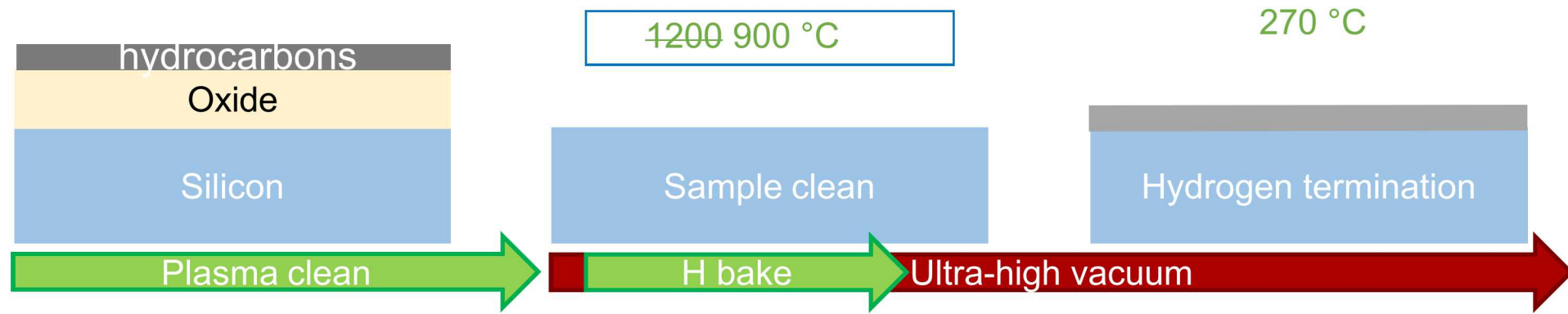


Challenges:

- Elevated pressure
 - After wafer clean – proceed to doping, or preserve surface with H?
 - Kinetics of dopant incorporation
- Low temperature growth
 - Only MBE known to work at these temperatures
 - Radical growth? Beam-assisted? Chemical - TCS/DS?

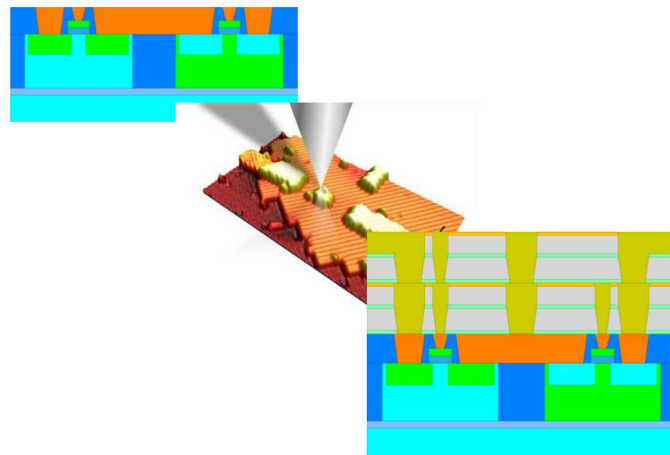
Looking for partners.
Skywater Technologies can host a tool.

APAM process flow

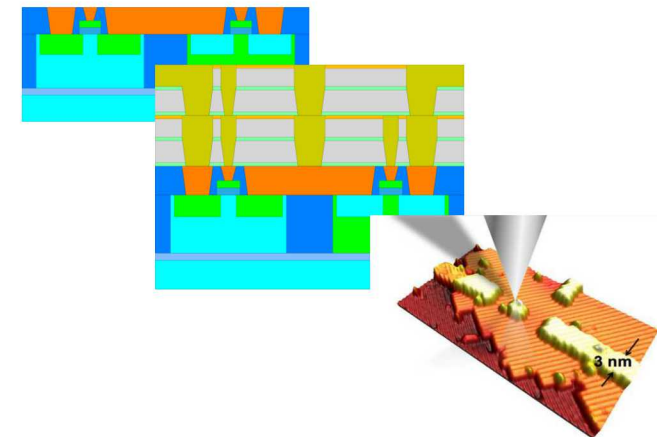


[Ward, Appl. Phys. Lett. \(2017\)](#)

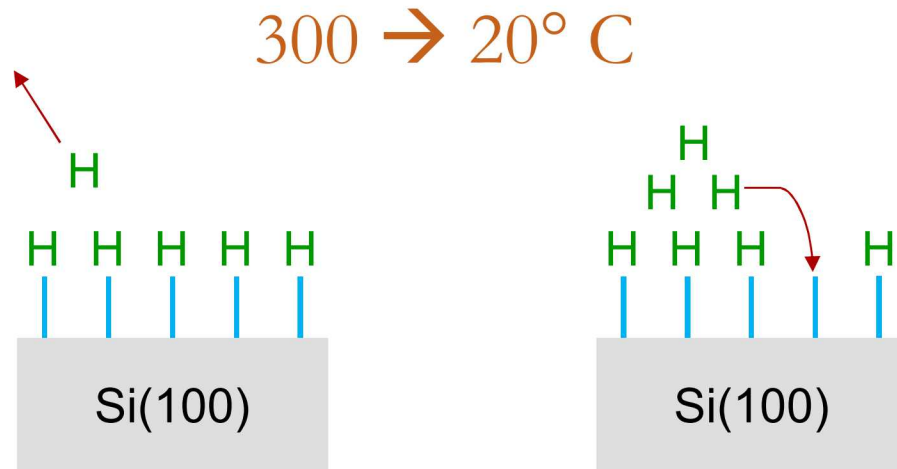
Direct Integration: can we do wafer-scale APAM processing?



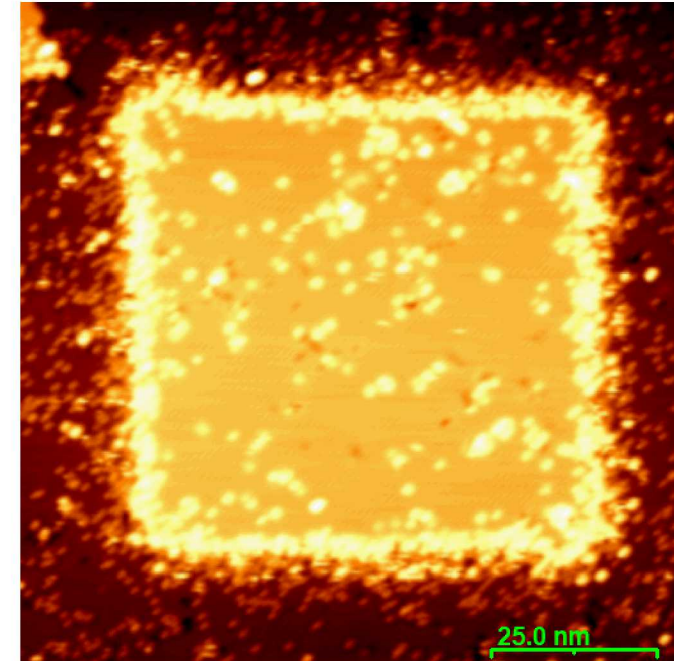
Post-CMOS integration: how low can we drive down process temperatures, even with sub-optimal results?



Hydrogen passivation & lithography



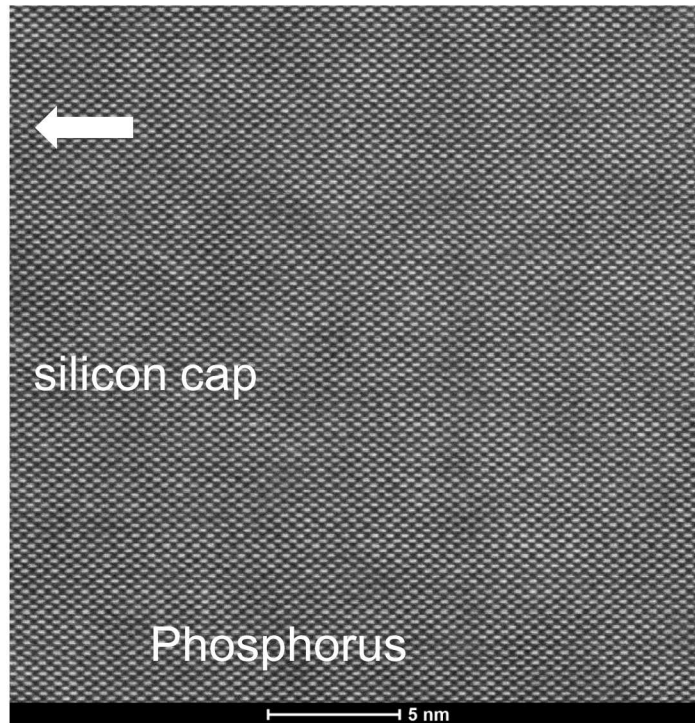
20° C: Hydrogen physisorbed on
top of hydrogen passivated silicon



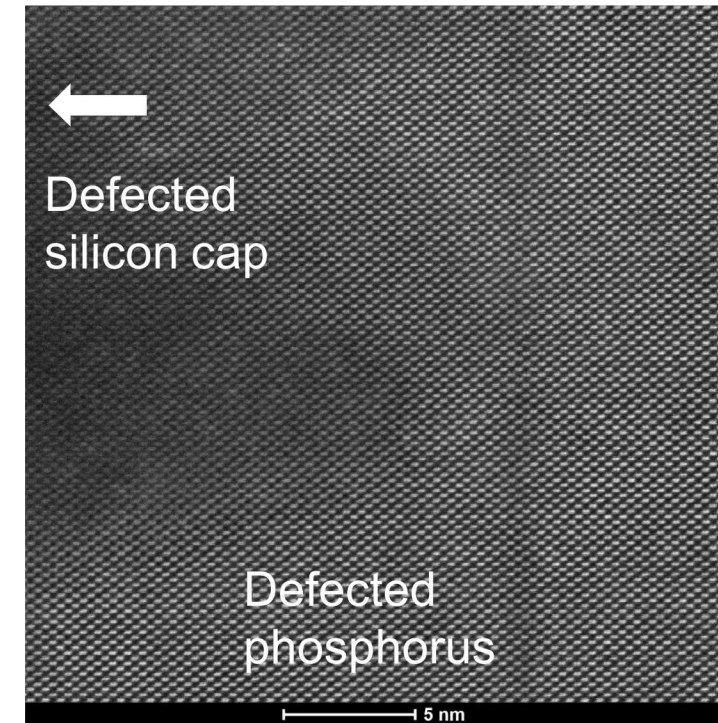
Lithography now requires multiple
passes, but works great!

Phosphorus incorporation and capping

350 → 200° C



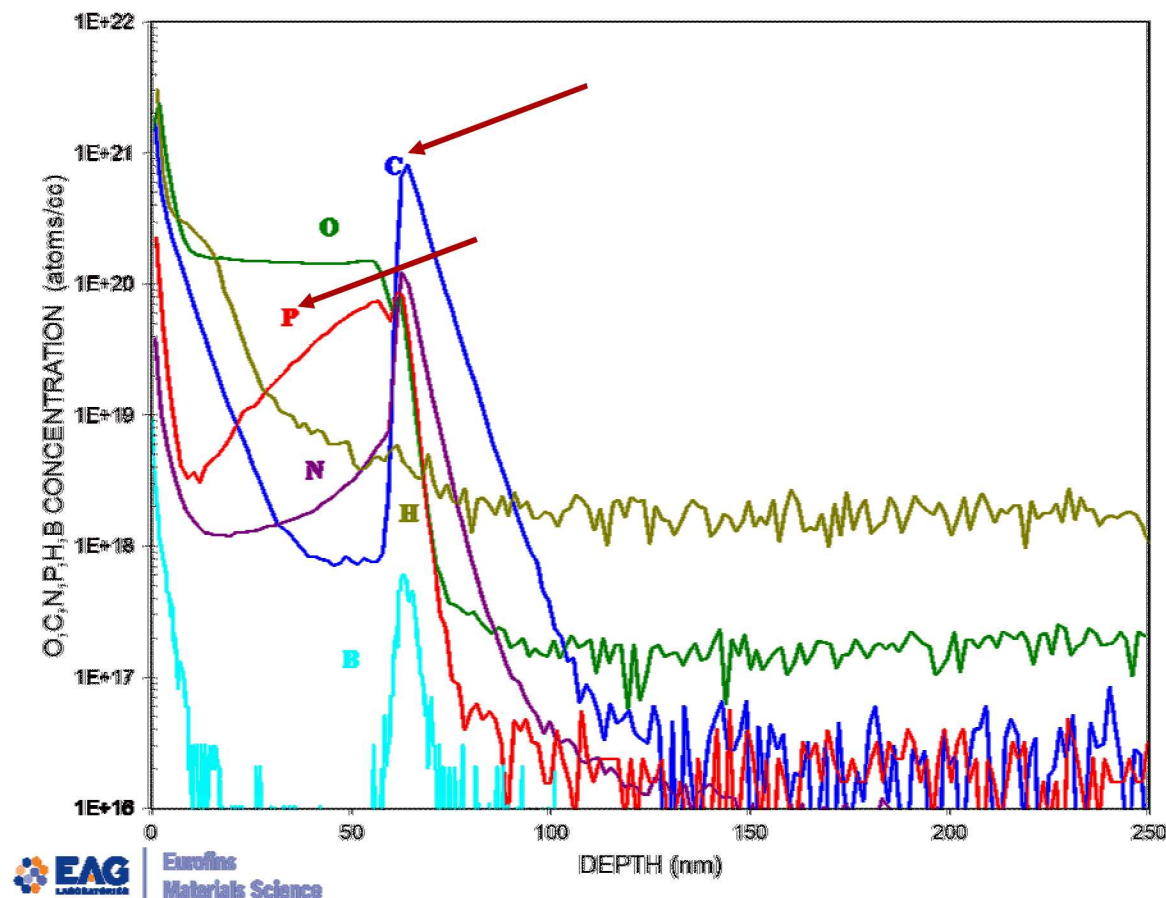
$n \sim 1.7 \times 10^{14} \text{ cm}^{-2}$
 $\mu \sim 50 \text{ cm}^2/\text{V-s}$
 $\sigma \sim 2 \text{ mS/sq.}$



$n \sim 1.4 \times 10^{14} \text{ cm}^{-2}$
 $\mu \sim 20 \text{ cm}^2/\text{V-s}$
 $\sigma \sim 0.6 \text{ mS/sq.}$

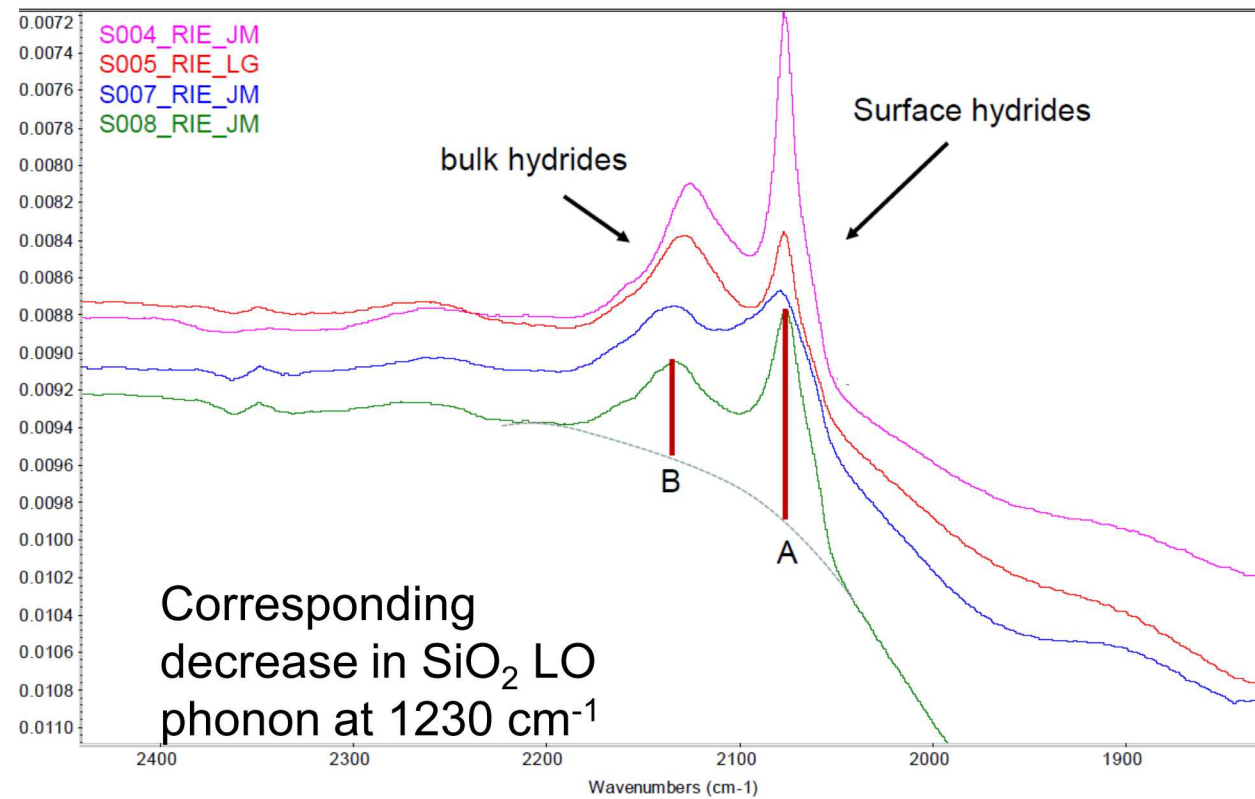
Electrical transport
degrades only by a factor
of 3 vs. optimal process

Reduced temperature sample prep



Wet preparation is not working
Hines, J. Phys. Chem. C (2009)

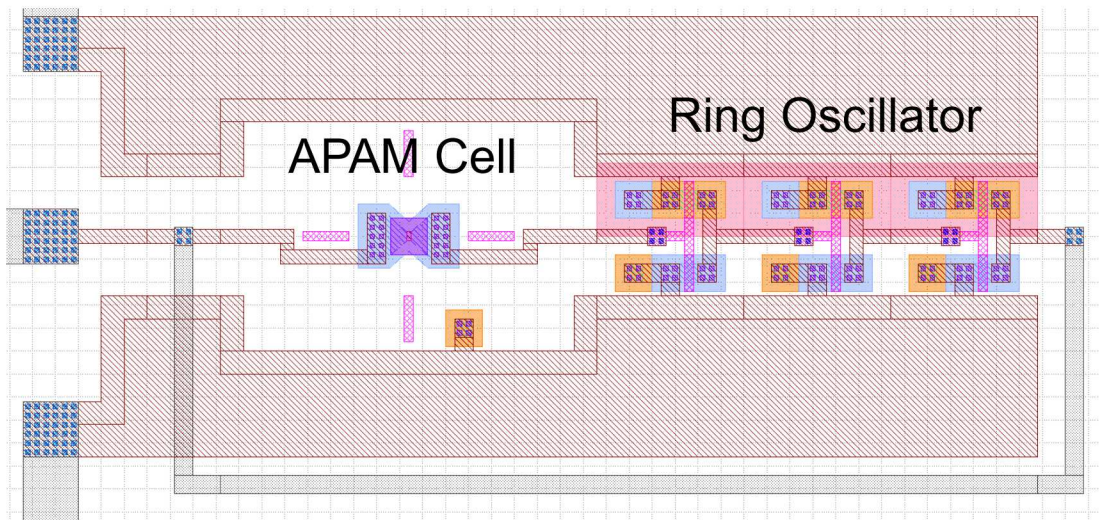
IR differential spectra of hydrogen stretch region



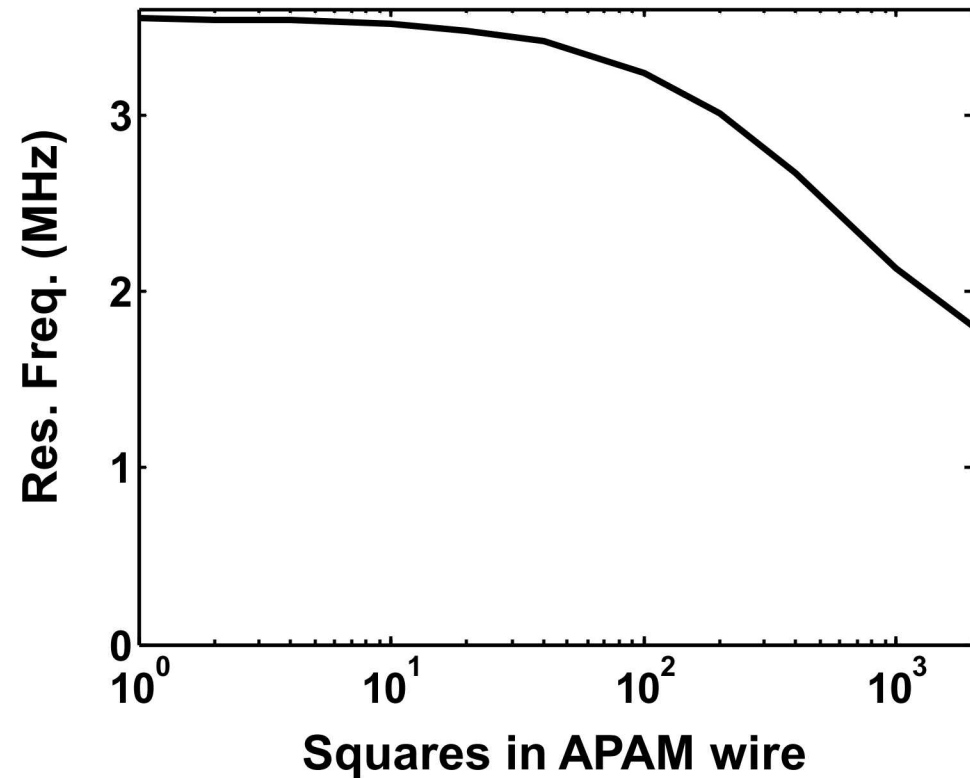
RIE has shown promising results, but
reproducibility problems. Trying in a
variety of tools.

What's next? Go for it!

Physical Layout



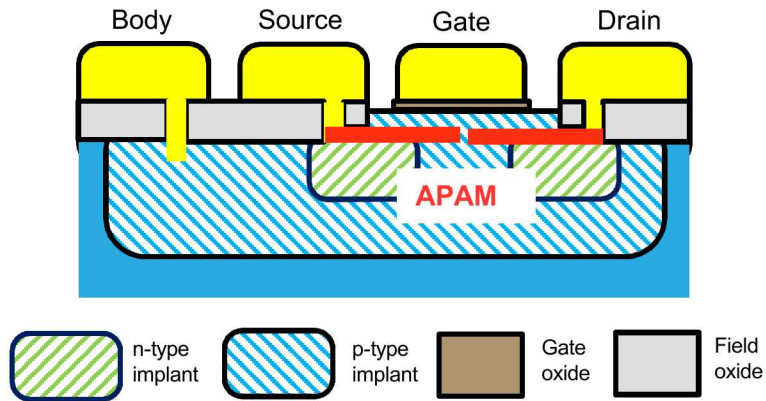
Full-stack simulation



Measure effect of APAM on real CMOS parts

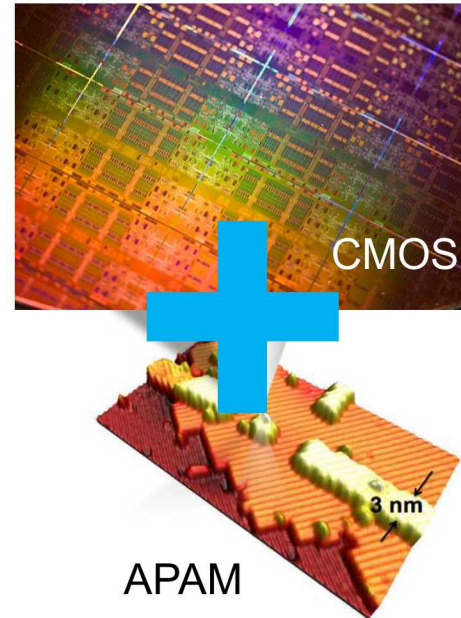
How to get to digital electronics at the atomic scale?

1. APAM devices



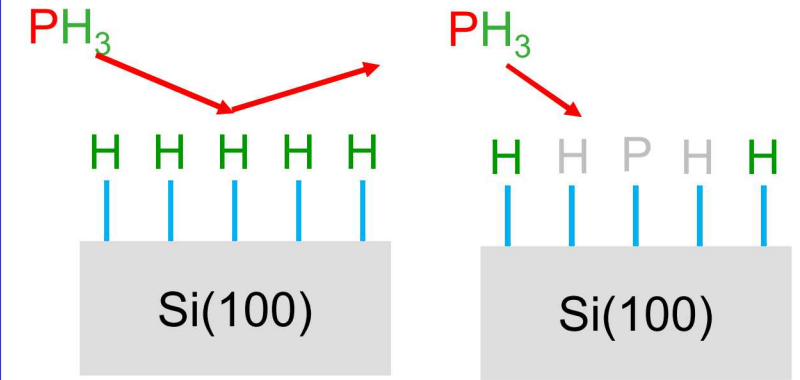
- ✓ Surface gated APAM devices
- ✓ Operate at room temperature
- ❑ APAM transistor

2. CMOS integration



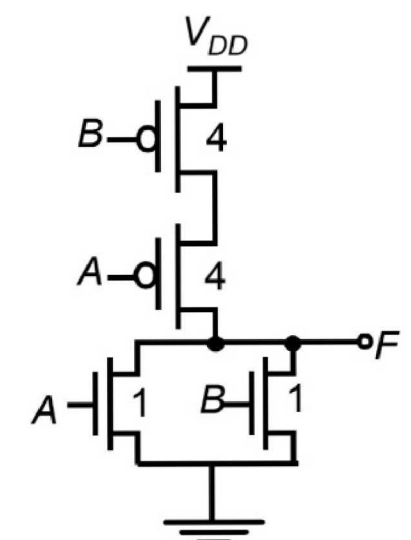
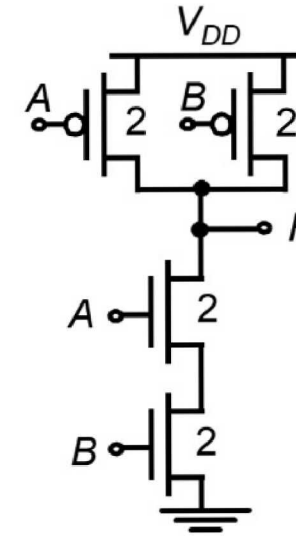
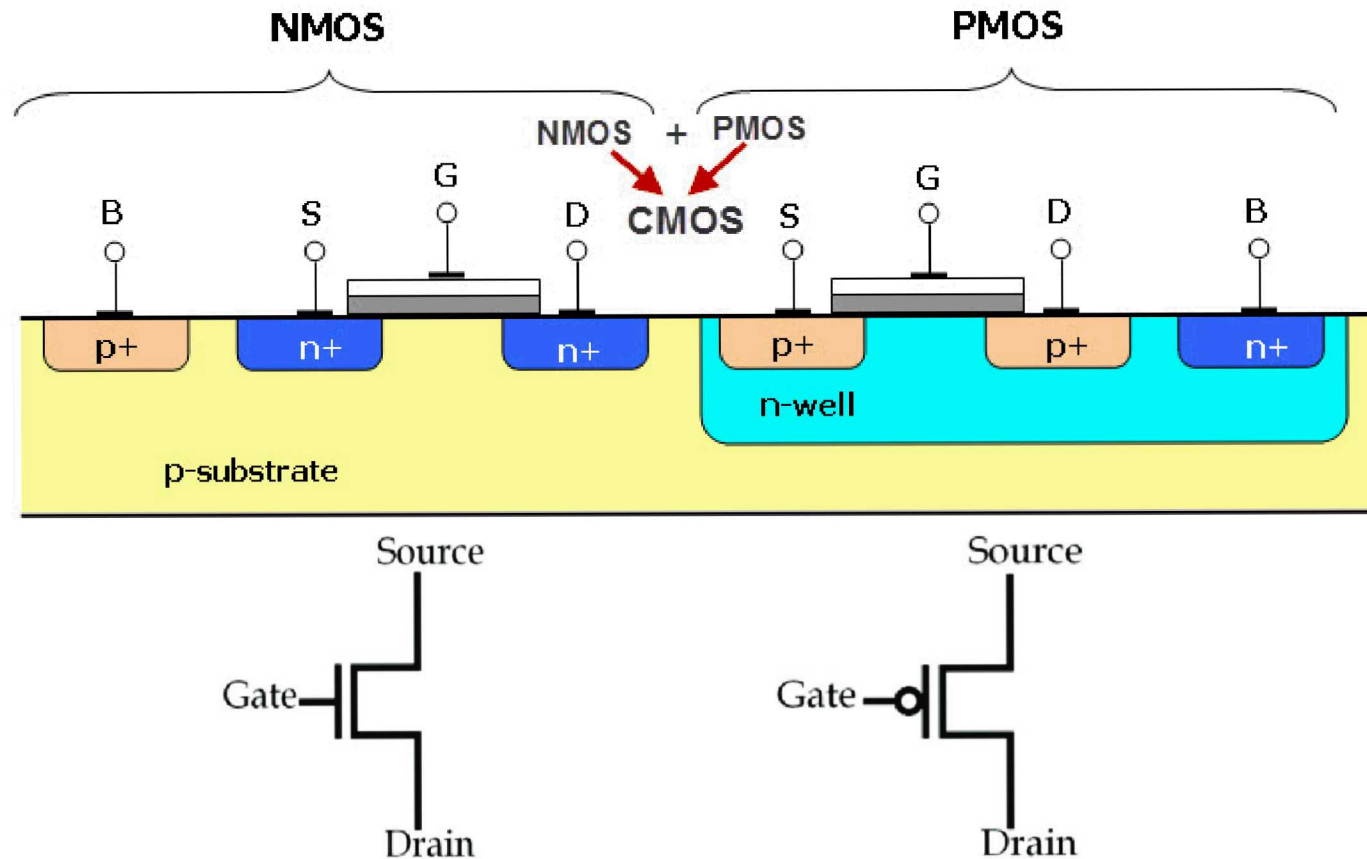
- ✓ Direct integration: wafer-scale APAM litho
- ❑ Wafer-scale APAM process
- ✓ Post-CMOS: reduction of process temperatures
- ❑ Reduced temp. sample prep

3. APAM toolkit



- ❑ One working chemistry

Need an acceptor chemistry

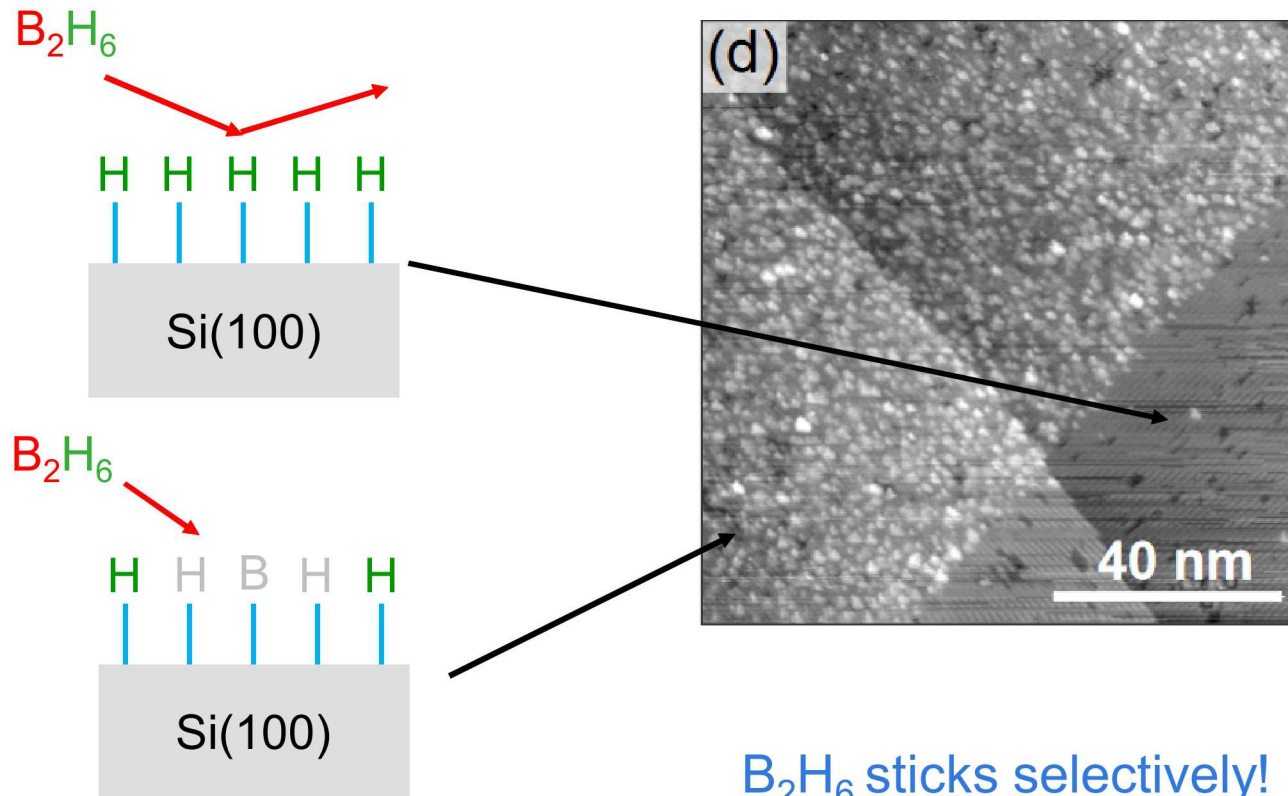


Efficient digital logic requires complementary switches

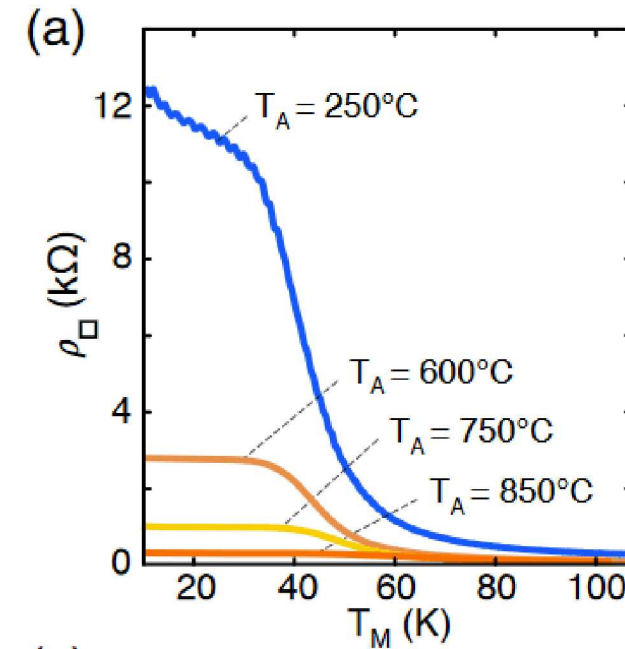
Complementary devices require acceptors.

Diborane provides selective p-type doping

Skeren, arXiv:1912.06188

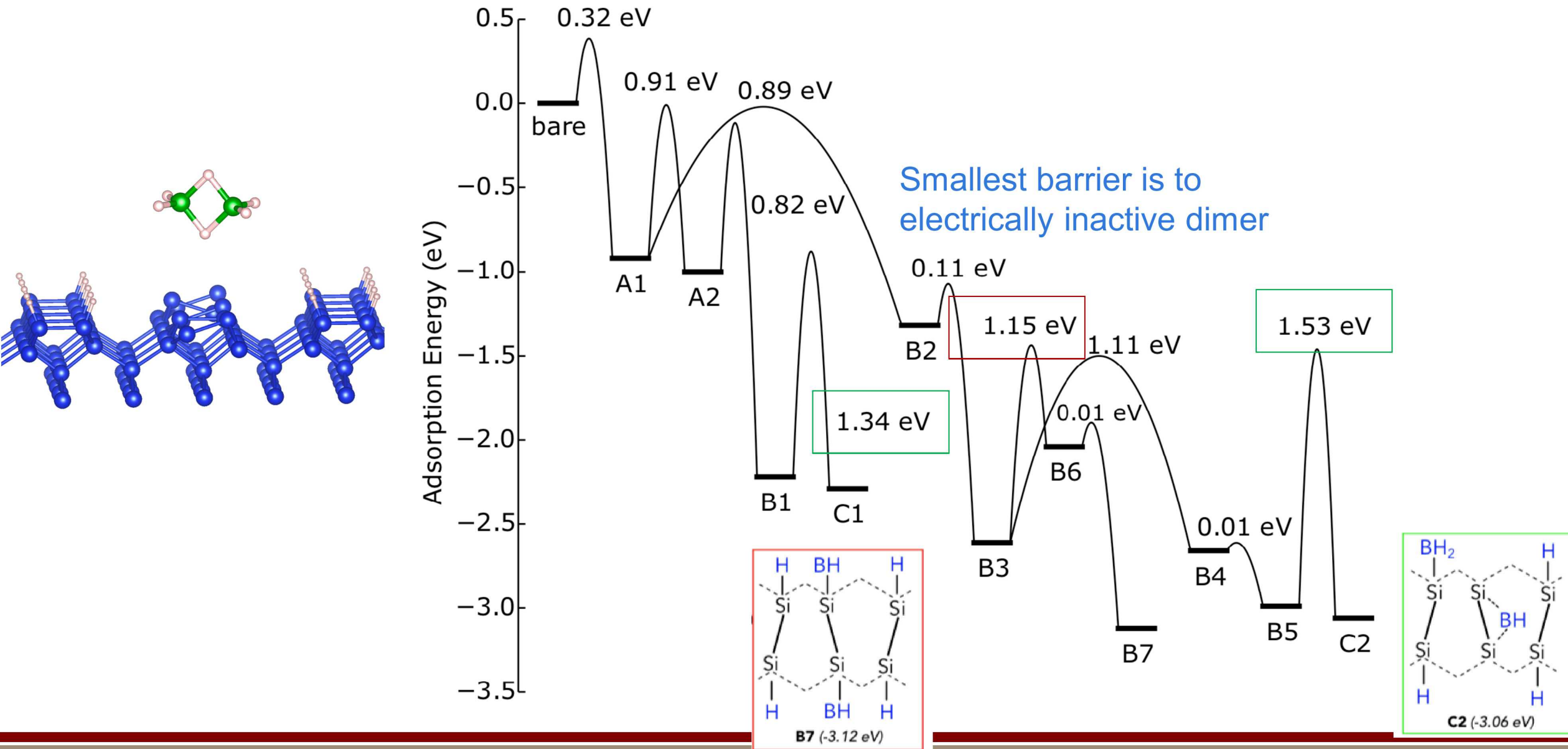


B_2H_6 sticks selectively!

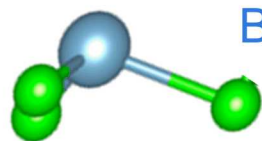


Electrical quality is questionable

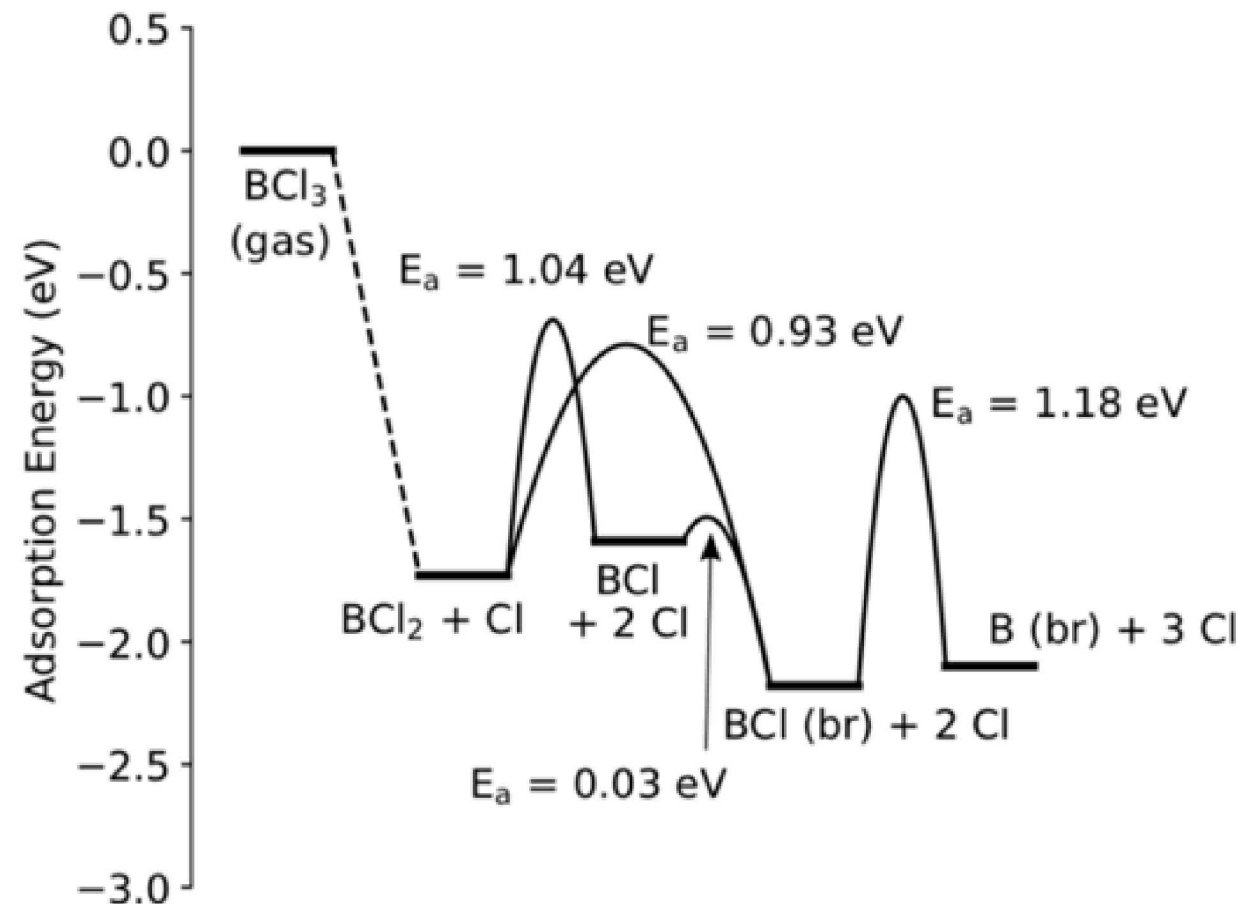
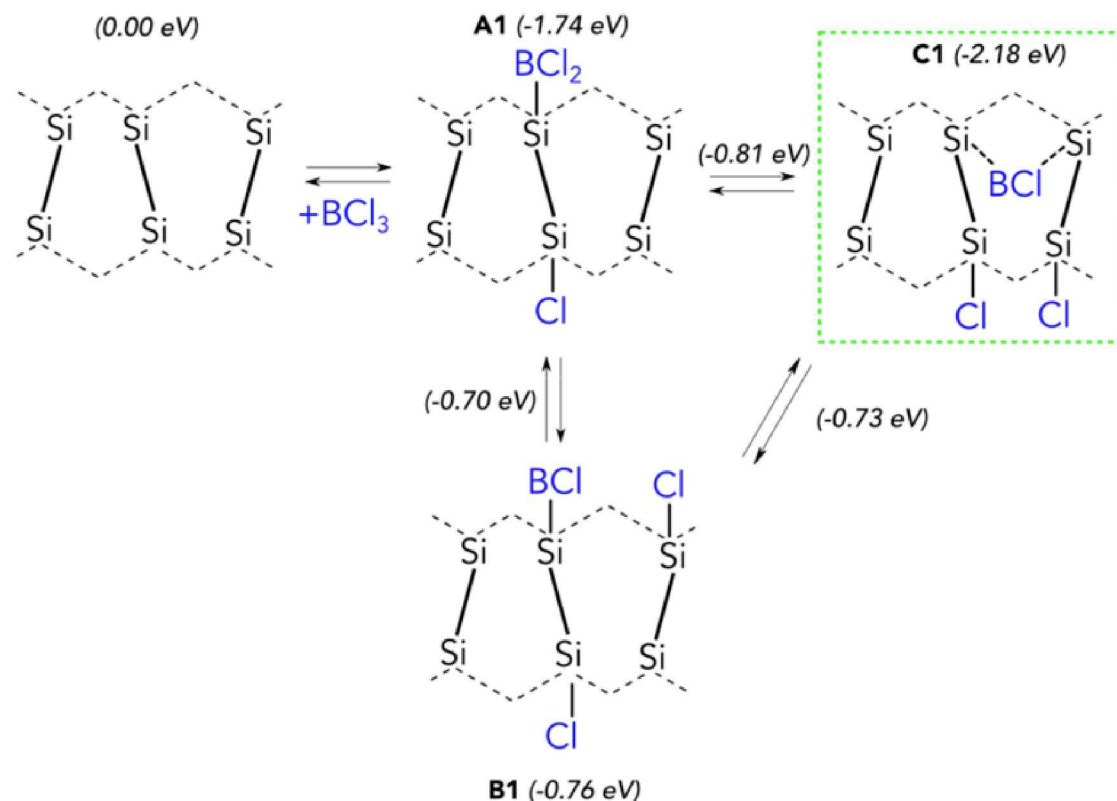
Why does diborane have a high resistivity?



Acceptor chemistry with monomer precursor

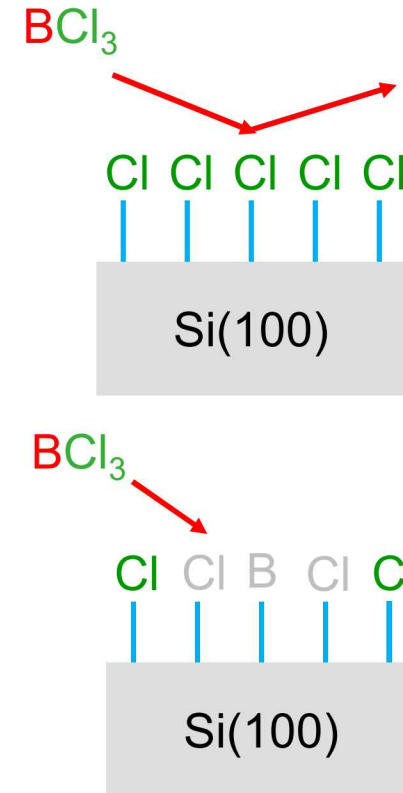
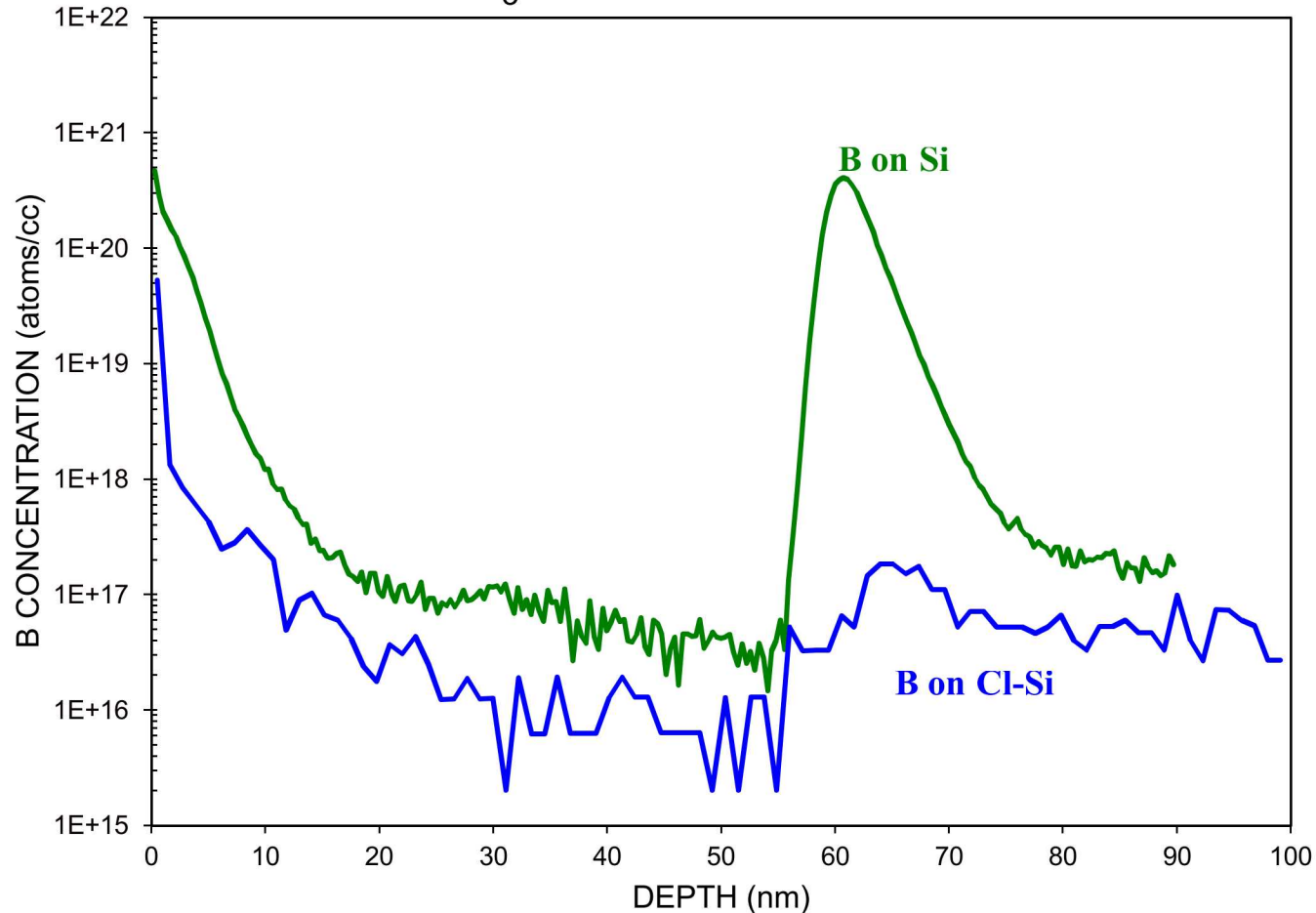


BCl_3 is a monomer, modest barrier

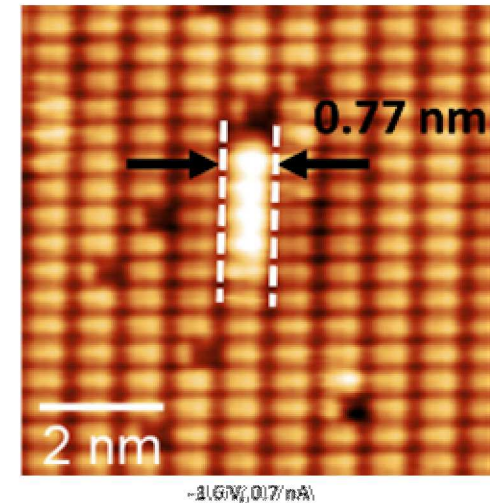


BCl_3 selective to Cl/bare silicon

3.6 L BCl_3 on bare and Cl-terminated Si

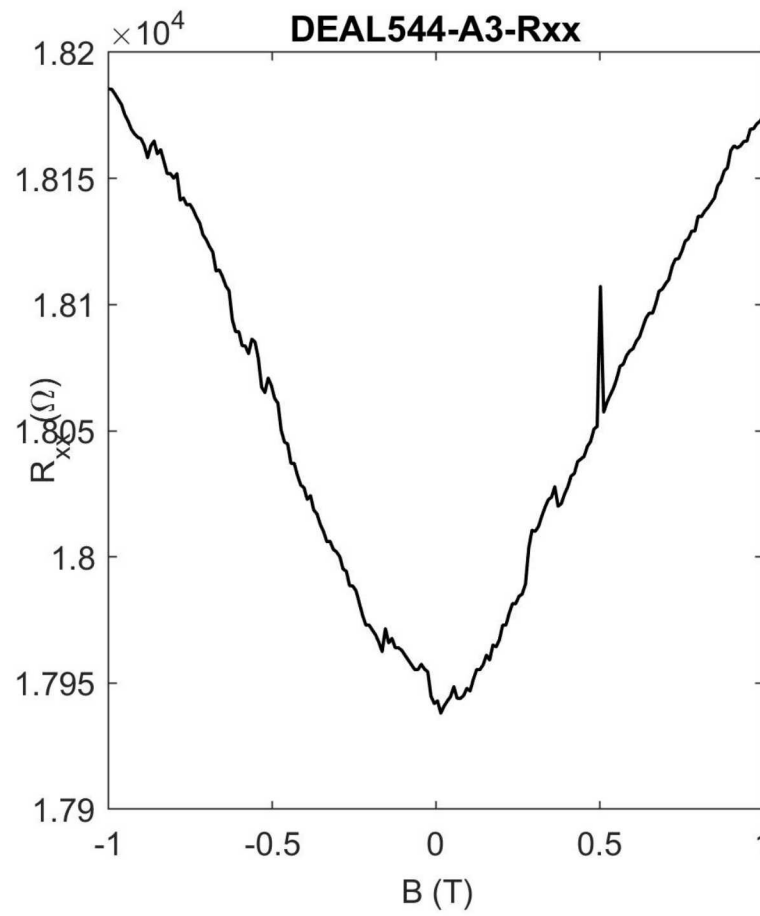
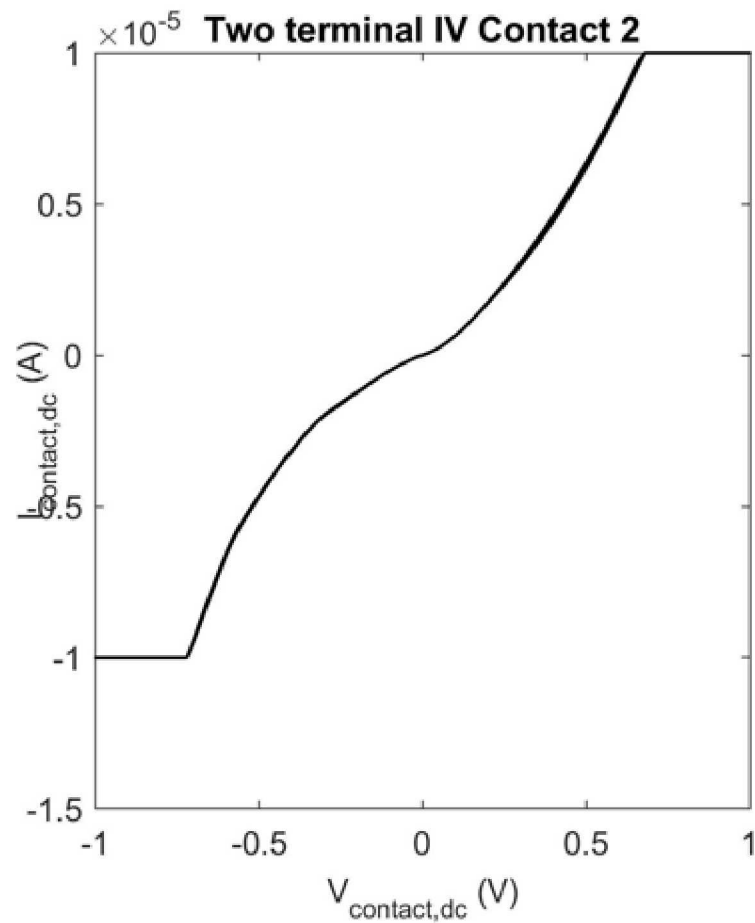


Atomic Precision
Patterning



[Dwyer, J. Phys. Chem. A \(2019\)](#)

First electrical measurements

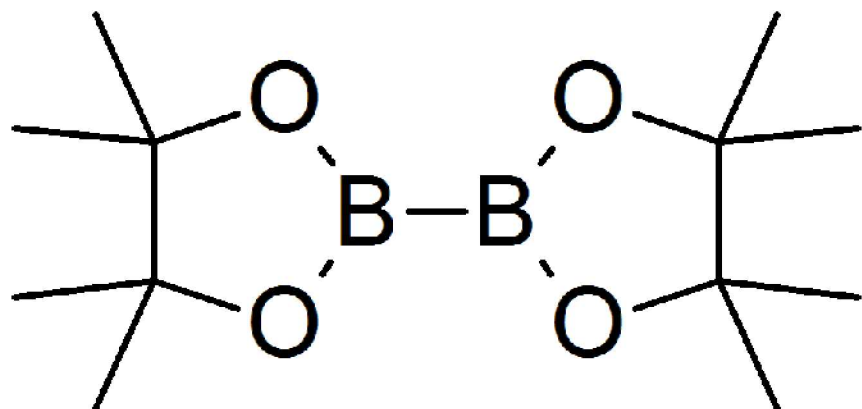


Resistivity of $2.25 \text{ k}\Omega/\text{sq}$

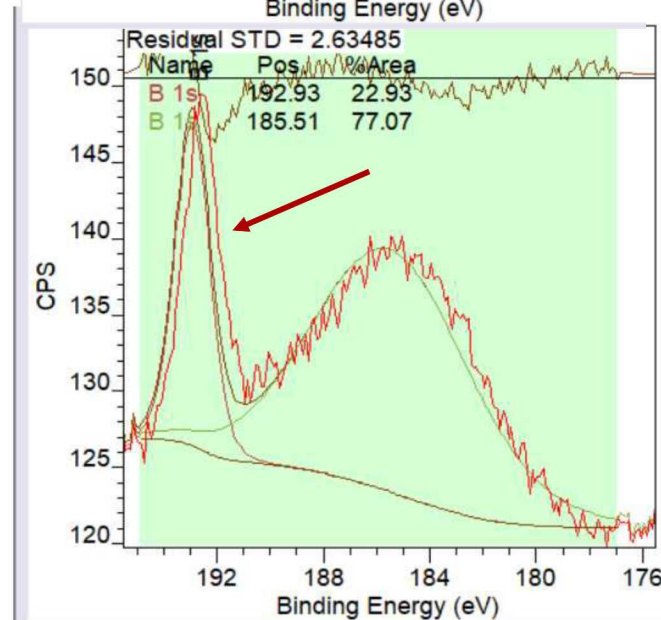
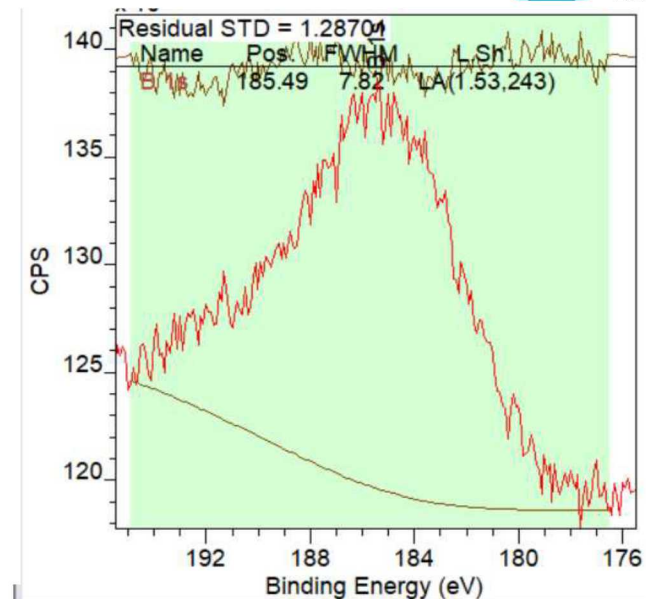
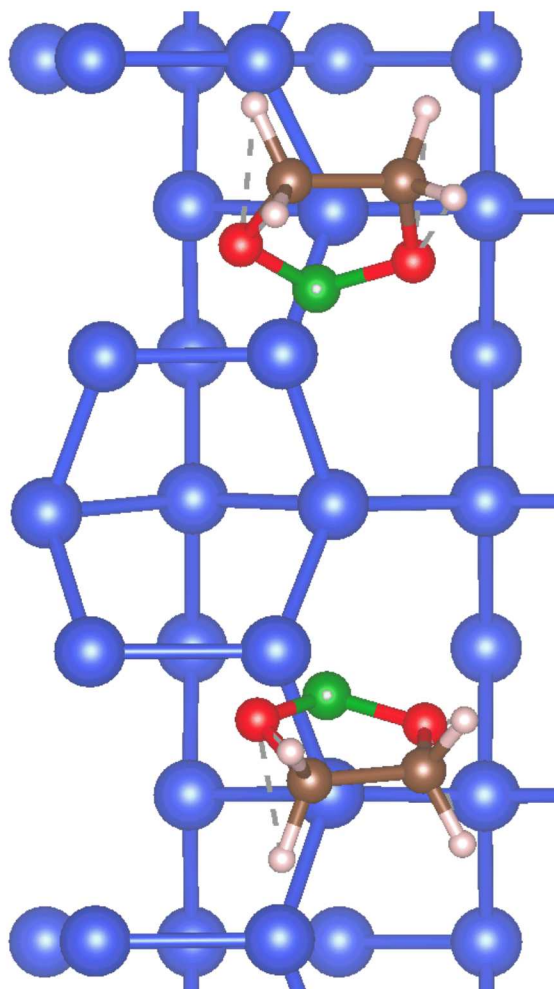
- 4x worse than phosphine
- 6x better than diborane

What's next?

Need wider range of chemistries,
but hard to try... try wet chemistry

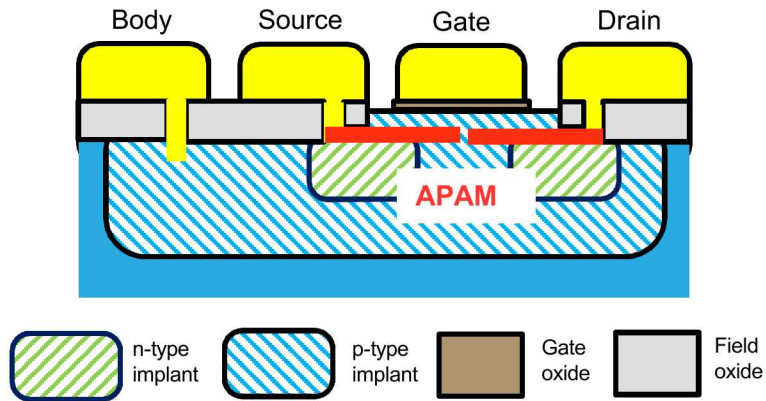


How do people clean up
wet chemistry?



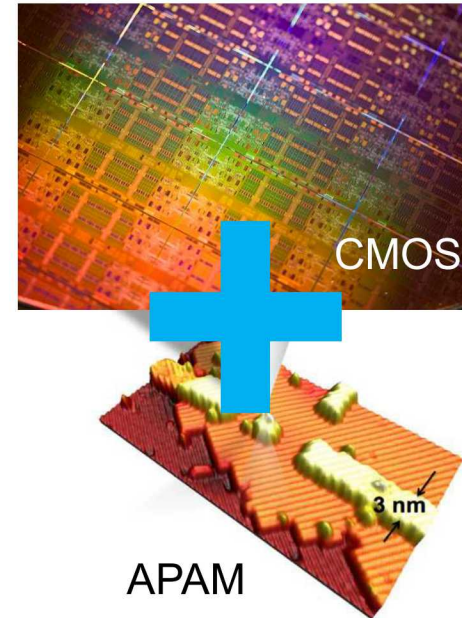
How to get to digital electronics at the atomic scale?

1. APAM devices



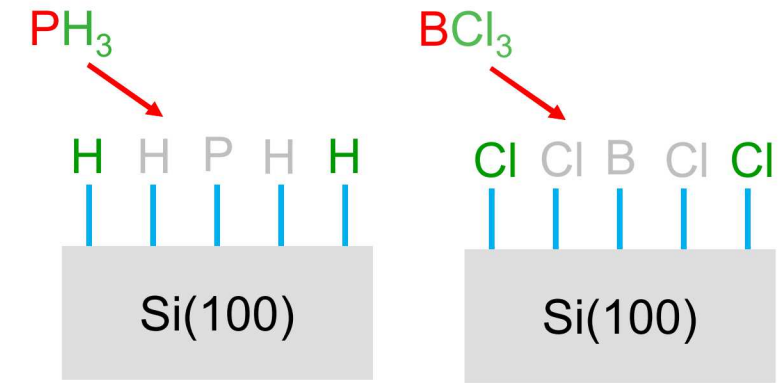
- ✓ Surface gated APAM devices
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2. CMOS integration



- ✓ Direct integration: wafer-scale APAM litho
- ❑ Wafer-scale APAM process
- ❑ Post-CMOS: Reduced temp. sample prep

3. APAM toolkit



- ✓ Working chemistry with PH_3 / H and BCl_3 / Cl
- ❑ Chemistries for oxides, metal, etching, etc.

Thanks to...

Devices

Lead: Shashank Misra

Modeling

Lead: Suzey Gao

Integration

Lead: David Scrymgeour

Manufacturability

Lead: George Wang

Measurement: Lisa Tracy, Tzu-Ming Lu, Albert Grine, David Scrymgeour, Ping Lu, Aaron Katzenmeyer

Microfabrication: David Scrymgeour, Andrew Leenheer, Dan Ward, DeAnna Campbell, Mark Gunter, Phillip Gamache, Sean Smith, Troy England, Andrew Starbuck, Steve Carr, Reza Arghavani

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Surface Science: Bob Butera (LPS), Kevin Dwyer (LPS), Andrew Teplyakov (Delaware), Alex Shestopalov (Rochester), Ezra Bussmann, Scott Schmucker, Evan Anderson, Joe Lucero, Jeff Ivie, Fabian Pena, Aaron Katzenmeyer, George Wang, Esther Frederick, Igor Kolesnichenko, David Wheeler, Mike Marshall

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